

# Lawrence Berkeley National Laboratory

## Recent Work

**Title**

COMPUTER PROGRAMS FOR ELLIPSOMETRY

**Permalink**

<https://escholarship.org/uc/item/49q0h24f>

**Author**

Mathieu, H. Jorg.

**Publication Date**

1973-05-01

COMPUTER PROGRAMS FOR ELLIPSOMETRY

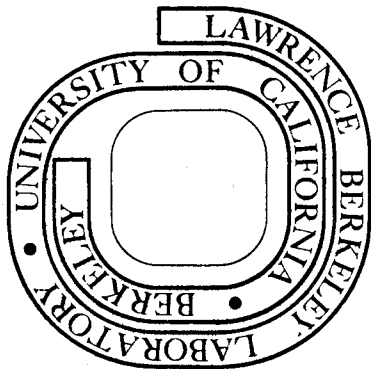
H. Jörg Mathieu

May 1973

Prepared for the U.S. Atomic Energy Commission  
under Contract W-7405-ENG-48

**For Reference**

Not to be taken from this room



## **DISCLAIMER**

This document was prepared as an account of work sponsored by the United States Government. While this document is believed to contain correct information, neither the United States Government nor any agency thereof, nor the Regents of the University of California, nor any of their employees, makes any warranty, express or implied, or assumes any legal responsibility for the accuracy, completeness, or usefulness of any information, apparatus, product, or process disclosed, or represents that its use would not infringe privately owned rights. Reference herein to any specific commercial product, process, or service by its trade name, trademark, manufacturer, or otherwise, does not necessarily constitute or imply its endorsement, recommendation, or favoring by the United States Government or any agency thereof, or the Regents of the University of California. The views and opinions of authors expressed herein do not necessarily state or reflect those of the United States Government or any agency thereof or the Regents of the University of California.

COMPUTER PROGRAMS FOR ELLIPSOMETRY

Contents

Abstract . . . . . v

I. Introduction . . . . . 1

II. FORTRAN IV Computer Program "CMER" . . . . . 3

III. FORTRAN IV Computer Program "CMOC" . . . . . 11

IV. FORTRAN IV Computer Program "OZOM" . . . . . 17

V. FORTRAN IV Computer Program "FILM" . . . . . 25

VI. FORTRAN IV Computer Program "A3PLOT" . . . . . 34

VII. FORTRAN IV Computer Program "PSIDEL" . . . . . 48

VIII. FORTRAN IV Computer Program "LAYER" . . . . . 54

IX. FORTRAN IV Computer Program "FPLOT" . . . . . 59

Acknowledgement . . . . . 69

References . . . . . 70

Tables . . . . . 71

COMPUTER PROGRAMS FOR ELLIPSOMETRY

H. Jörg Mathieu

Inorganic Materials Research Division, Lawrence Berkeley Laboratory  
and Department of Chemical Engineering; University of California  
Berkeley, California 94720

ABSTRACT

This report gives a collection of computer programs in FORTRAN IV language which are used in ellipsometry. Two programs (programs CMER and CMOC) can be used to determine optical parameters of bare surfaces. The correction of the deviation of the compensator from ideal retardation and transmission has been incorporated in the computation of optical constants of bare surfaces derived from measurements in one zone (program OZOM). Two other programs permit the use of ellipsometer azimuth readings as input and output variables to determine the refractive index and film thickness of a film-covered surface (programs FILM and A3PLOT). This is of advantage in case of comparison of calculated and measured polarizer- and analyzer-readings which are recorded from an automatic ellipsometer. Another program converts ellipsometer azimuth readings into relative phase and amplitude parameter ( $\Delta$ ,  $\psi$ ) (program PSIDEL).

## I. Introduction

In ellipsometry, the change of the state of polarization due to reflection is measured and interpreted in terms of properties of the reflecting surface. This technique is capable of examining surfaces in any optically transparent environment. The reflection of light from surfaces and thin films has been discussed by various authors.<sup>2-4</sup>

Two parameters are measured in ellipsometry: the change in relative amplitude ( $\psi$ ) and relative phase ( $\Delta$ ) of two orthogonal quantities of light due to reflection. From these two measured quantities two parameters of the reflecting surface can be derived. For a bare surface, this can be the real and imaginary part of the complex refractive index. For a surface covered with a transparent film, the real refractive index of the dielectric film and the thickness can be determined, if the optical constants of the substrate are known. Sometimes it is possible to determine more than two unknowns, i.e., thickness and complex refractive index of an absorbing film, if sufficiently narrow limits can be given for the unknowns.

The exact classical equations<sup>10</sup> cannot be solved explicitly<sup>11</sup> and are too tedious for normal calculations in all but a few cases. The availability of high-speed computers therefore is an important factor in ellipsometry. Such programs given below can be used with ellipsometers either manually or automatically operated.

The first two programs (CMER and CMOC) can be used to determine optical parameters of bare surfaces from ellipsometer readings and vice versa. The deviation of the compensator from ideal retardation and transmission has been considered in program OZOM. The next two programs (FILM and A3PLOT) allow to compare calculated with measured

azimuth readings of the ellipsometer of film covered surfaces. For the application of an automatic ellispometer, which records the azimuth readings of analyzer and polarizer, it is very convenient to compare calculated and measured azimuth readings. In the case of manual operation, program SPIDEL can be used to convert ellispometer azimuth readings into relative phase and amplitude parameters ( $\Delta$ ,  $\psi$ )

All formulas derived below are based on the Nebraska convention.<sup>12</sup>

## II. FORTRAN IV Computer Program "CMER"

This program computes the ellipsometric parameters  $\Delta$  and  $\psi^*$  from given values of the complex refractive index  $n_c$  of bare surfaces using the complex formalism. \*\* Application of the electromagnetic theory<sup>3,4</sup> shows that the Fresnel equations can be adopted to describe reflection from absorbing media by introduction of a complex refractive index  $n_c$ :

$$n_c = n - ik \quad (1)$$

$n_c$  is defined here to be a material constant, independent of angle of incidence.<sup>5,6</sup> Application of Snell's law

$$n_o \sin\phi = n_c \sin\phi'_c \quad (2)$$

results in a complex angle of refraction  $\phi'_c$ , which provides a valid formalism, but no recognisable physical meaning. ( $n_o$  real refractive index of incident medium,  $\phi$  angle of incidence). The Fresnel equations<sup>7</sup> relate the amplitude of reflection coefficients to the angles of incidence and refraction.

$$r_p = \frac{\tan(\phi - \phi'_c)}{\tan(\phi + \phi'_c)} \quad (3)$$

$$r_s = -\frac{\sin(\phi - \phi'_c)}{\sin(\phi + \phi'_c)} \quad (4)$$

\*Derivation of  $\Delta$  and  $\psi$  from ellipsometer azimuth of analyzer, polarizer and quarter-wave plate can be found in Table I.

\*\* A previous program "MER"<sup>1</sup>, which avoided the complex formalism<sup>2</sup> and was based on earlier work,<sup>13</sup> leads to the same results.



Using trigonometric formulas, one gets

$$\cos(\phi + \phi'_c) = \cos\phi \cos\phi'_c - \sin\phi \sin\phi'_c \quad (5)$$

$$\cos(\phi - \phi'_c) = \cos\phi \cos\phi'_c + \sin\phi \sin\phi'_c \quad (6)$$

$$\sin(\phi + \phi'_c) = \sin\phi \cos\phi'_c + \cos\phi \sin\phi'_c \quad (7)$$

$$\sin(\phi - \phi'_c) = \sin\phi \cos\phi'_c - \cos\phi \sin\phi'_c \quad (8)$$

where  $\sin\phi'_c$  and  $\cos\phi'_c$  are given by applying Eq. (2)

$$\sin\phi'_c = (n_o \sin\phi)/n_c \quad (9)$$

$$\cos\phi'_c = \sqrt{1 - \sin\phi'_c{}^2} = \sqrt{\frac{n_c^2 - n_o^2 \sin^2\phi}{n_c^2}} \quad (10)$$

The Fresnel coefficients represent the ratio of reflected to incident electric field amplitude and are different for s and p components<sup>4</sup>

$$r_p = \frac{|E''_p|}{|E_p|} e^{i(\epsilon''_p - \epsilon_p)} = \frac{E''_p}{E_p} \quad (11)$$

$$r_s = \frac{|E''_s|}{|E_s|} e^{i(\epsilon''_s - \epsilon_s)} = \frac{E''_s}{E_s} \quad (12)$$

with the modulus representing the amplitude attenuation

$$|r_p| = \frac{|E''_p|}{|E_p|} \quad (13)$$

$$|r_s| = \frac{|E''_s|}{|E_s|} \quad (14)$$

and the argument representing the (absolute) change in phase due to reflection

$$\delta_p = \epsilon_p'' - \epsilon_p \quad (15)$$

$$\delta_s = \epsilon_s'' - \epsilon_s \quad (16)$$

Thus, the complex Fresnel reflection coefficients can also be expressed as

$$r_p = |r_p| e^{i\delta_p} \quad (17)$$

$$r_s = |r_s| e^{i\delta_s} \quad (18)$$

The ellipsometer determines the ratio  $\rho$  of the (complex) reflection coefficients for p and s components

$$\rho = \frac{r_p}{r_s} = \frac{|r_p|}{|r_s|} e^{i(\delta_p - \delta_s)} \quad (19)$$

which is often given in a simplified form as

$$\rho = \tan\psi e^{i\Delta} \quad (20)$$

Comparison with Eq. (19) leads to the definitions

$$\tan\psi = \frac{|r_p|}{|r_s|} \quad (21)$$

$$\Delta = \delta_p - \delta_s \quad (22)$$

The absolute change in phase due to reflection then is expressed by

$$\delta_p = \tan^{-1} \frac{\text{Im}(r_p)}{\text{Re}(r_p)} \quad (23)$$

$$\delta_s = \tan^{-1} \frac{\text{Im}(r_s)}{\text{Re}(r_s)} \quad (24)$$

The ellipsometric parameters  $\Delta$  and  $\psi$  can be computed from Eq. (19)

to give

$$\Delta = \tan^{-1} \frac{\text{Im}(\rho)}{\text{Re}(\rho)} \quad (25)$$

$$\psi = \tan^{-1} (|\rho|) \quad (26)$$

Variables Employed in CMER Program

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
TNO	$n_o$	Refractive index of transparent incident medium
TNC	$n_c = n - ik$	Complex refractive index of metal
PHID	$\phi(\text{deg})$	Angle of incidence
PHI	$\phi(\text{rad})$	Angle of incidence
DELD	$\Delta(\text{deg})$	Rel. phase change $\delta_p - \delta_s$
PSID	$\psi(\text{deg})$	$\tan^{-1}$ of rel. amplitude attenuation
RHO	$\rho$	Ratio of reflexion coefficients of p- and s-component: $r_p/r_s$
RHO REAL	$\text{Re}(\rho)$	Real part of $\rho$
RHO IMAG	$\text{Im}(\rho)$	Imaginary part of $\rho$
RPC	$r_p$	Reflection coeff. of p-component (complex)
RSC	$r_s$	Reflection coeff. of s-component (complex)
RP	$ r_p $	Modulus of $r_p$
RS	$ r_s $	Modulus of $r_s$
DELPD	$\delta_p$	Absolute phase change with respect to incident wave (p-component)
DELSD	$\delta_s$	Absolute phase change with respect to incident wave (s-component)
ABSRHO	$ \rho $	Modulus of $\rho$

Input Data for the Program "CMER"

The input data are punched on cards as illustrated below:

<u>Card</u>	<u>Col. 1-10</u>	<u>Col. 11-20</u>
1	TITLE	(Col. 1-80)
2	$\phi$ (deg)	$n_o$
3	n	-k

Cards 1-3 constitute one set. Three blank cards must follow the last set of data. The program together with a sample output is given below.

CMER

```
PROGRAM CMER (INPUT,OUTPUT)
C THIS PROGRAM IS INDEPENDENT OF ANGLE READINGS
C THIS PROGRAM COMPUTES THE PARAMETERS FOR METALLIC
C REFLECTION FROM VALUES OF TNC,TNO AND PHID USING COMPLEX NUMBER
C
C COMPLEX PHO,TNC,S2,S3,S4,C2,C3,C4,RPC,RSC
C
C DIMENSION TITLE (8)
5 READ 76,TITLE
10 1 READ 10,PHID,TNO
10 10 FORMAT (2F10.0)
76 76 FORMAT (8A10)
20 PRINT 77,TITLE
77 77 FORMAT (1H0,8A10)
26 2 READ 20,TNC
20 20 FORMAT (2F10.0)
34 IF (TNC) 12,12,4
37 4 CONTINUE
C
37 3 PRINT 30,PHID,TNC,TNO
30 30 FORMAT (1H0,7HPHTD = ,F10.7,/, 6HTNC = ,F10.7,F10.7,/,6HTNO = ,
1F10.7,/)
2,8X,2HRP,10X,5HDELDP,7X,2HRS,10X,5HDELSD)
C
51 ALPHA=0.01745329252
52 PHI=PHID*ALPHA
54 S1 = SIN (PHI)
56 C1 = COS (PHI)
60 S2 = (TNO*S1)/TNC
72 C2 = CSQRT (1 - S2*S2)
111 C3 = (C1*C2)+(S1*S2)
123 C4 = (C1*C2)-(S1*S2)
135 S3=S1*C2-C1*S2
147 S4=S1*C2+C1*S2
C
162 RPC=(S3*C4)/(C3*S4)
205 RSC=-S3/S4
215 RHO=RPC/RSC
C
224 ABSPHO=CABS(RHO)
226 PSID=ATAN(ABSRHO)/ALPHA
231 DELD=ATAN2(AIMAG(PHO),REAL(RHO))/ALPHA
240 RP=CABS(RPC)
242 RS=CABS(RSC)
244 DELPD=ATAN2(ATMAG(RPC),REAL(RPC))/ALPHA
253 DELSD=ATAN2(AIMAG(RSC),REAL(RSC))/ALPHA
262 IF (DELPD.LT.0.0) DELPD = DELPD + 360.
266 IF (DELSD.LT.0.0) DELSD=DELSD + 360.
271 IF (DELD.LT.0.0) DELD=DELD + 360.
C
274 PRINT 80,PHO,ABSRHO,RP,RS,DELPD,DELSD,PSID,DELD
80 80 FORMAT (1H0,6HRHO = ,2F10.5,/,9HABSPHO = ,F10.5,
C/,5HRP = ,F10.5,10X,5HRS = ,F10.5,/,8HDELPD = ,F10.5,
C10X,8HDELSD = ,F10.5,/,7HPSID = ,F10.5,10X,7HDELD = ,
CF10.5,/)
320 GO TO 5
321 12 CONTINUE
322 END
```

Sample Output, Program CMER

CU            \*\*\* CMER \*\*\*                    WAVELENGTH = 546.1 NM

PHID = 75.0000000  
TNC = .9300000-2.3900000  
TNO = 1.0000000

RHO = .21477            .69411  
ABSRHO = .72658  
RP = .68342                    PS = .94061  
DELPD = 242.42742            DELSD = 169.62031  
PSID = 36.00128                    DELD = 72.80712

AG

PHID = 75.0000000  
TNC = .0820000-3.6100000  
TNO = 1.0000000

RHO = -.03543            .97840  
ABSRHO = .97904  
P = .97618                    PS = .99708  
DELPD = 264.15372            DELSD = 172.07960  
PSID = 44.39322                    DELD = 92.07412

AU

PHID = 75.0000000  
TNC = .3700000-2.3500000  
TNO = 1.0000000

RHO = .29254            .83065  
ABSRHO = .83066  
RP = .85737                    PS = .97255  
DELPD = 239.15379            DELSD = 168.55504  
PSID = 41.36907                    DELD = 70.59876

AL

PHID = 75.0000000  
TNC = .8100000-5.4700000  
TNO = 1.0000000

RHO = -.36791            .79721  
ABSRHO = .87801  
RP = .86658                    PS = .98699  
DELPD = 289.54345            DELSD = 174.77036

PSID = 41.28331                      DELD = 114.77209

CR

PHID = 75.0000000  
TNC = 2.9600000-3.4500000  
TNO = 1.0000000

RHO = -.14320                      .46518  
ABSRHO = .48672  
RP = .45298                      PS = .93069  
DELPD = 282.08206                      DELSD = 174.97189  
PSID = 25.95302                      DELD = 107.11018

NI

PHID = 75.0000000  
TNC = 1.4000000-2.5200000  
TNO = 1.0000000

RHO = .13240                      .61114  
ABSRHO = .62532  
RP = .57886                      PS = .92569  
DELPD = 248.85213                      DELSD = 171.07568  
PSID = 32.01860                      DELD = 77.77645

PT

PHID = 75.0000000  
TNC = 2.8600000-4.4200000  
TNO = 1.0000000

RHO = -.24625                      .52789  
ABSRHO = .58250  
RP = .55314                      PS = .94960  
DELPD = 290.26584                      DELSD = 175.25765  
PSID = 30.22084                      DELD = 115.00819

TA

PHID = 75.0000000  
TNC = 3.5000000-2.4000000  
TNO = 1.0000000

RHO = -.08503                      .32134  
ABSRHO = .33240  
RP = .30086                      PS = .90511  
DELPD = 280.68405                      DELSD = 175.86241  
PSID = 18.38686                      DELD = 104.82163

### III. FORTTRAN IV Computer Program "CMOC"

This computer program (Complex Metal Optical Constants) calculates the optical constants from relative phase change,  $\Delta$ , and arctangent of relative amplitude attenuation,  $\psi$ , using the complex formalism\*. This program just is the inversion of program "CMER". The ratio  $\rho$  of the (complex) reflection coefficients for p and s components can be determined from given values of  $\Delta$  and  $\psi$

$$\rho = \frac{r_p}{r_s} = \tan\psi \cdot e^{i\Delta} \quad (27)$$

Application of Fresnel's equations, Eqs. (3) and (4)

$$r_p = \frac{\tan(\phi - \phi'_c)}{\tan(\phi + \phi'_c)} = \frac{\frac{\sin(\phi - \phi'_c)}{\cos(\phi - \phi'_c)}}{\frac{\sin(\phi + \phi'_c)}{\cos(\phi + \phi'_c)}} \quad (28)$$

$$r_s = -\frac{\sin(\phi - \phi'_c)}{\sin(\phi + \phi'_c)} \quad (29)$$

leads to

$$\rho = -\frac{\cos(\phi + \phi'_c)}{\cos(\phi - \phi'_c)} \quad (30)$$

Use of Eqs. (5) through (8) give

$$\cos\phi'_c = \frac{\cos(\phi + \phi'_c) + \cos(\phi - \phi'_c)}{2 \cos\phi} \quad (31)$$

and

$$\sin\phi'_c = \frac{\cos(\phi - \phi'_c) - \cos(\phi + \phi'_c)}{2 \sin\phi} \quad (32)$$

\* A previous program "MOC"<sup>1</sup> which avoided the complex formalism<sup>2</sup> and was based on earlier work,<sup>13</sup> leads to the same results.



$$\tan\phi'_c = \frac{1 + \rho}{1 - \rho} \cdot \frac{1}{\tan\phi} \quad (33)$$

$\tan\phi'_c$  can be converted to  $\sin\phi'_c$  with

$$\sin\phi'_c = \frac{\tan\phi'_c}{\sqrt{1 + \tan^2\phi'_c}} \quad (34)$$

Then the (complex) refractive index is determined by

$$n_c = n - ik = \frac{n_o \sin\phi}{\sin\phi'_c} \quad (35)$$

Variables Used in Program "CMOC"

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
PHID	$\phi(\text{deg})$	Angle of incidence
PHI	$\phi(\text{rad})$	Angle of incidence
DELD	$\Delta(\text{deg})$	Rel. phase change
DEL	$\Delta(\text{rad})$	Rel. phase change
PSID	$\psi(\text{deg})$	Arctangent of rel. amplitude attenuation
PSI	$\psi(\text{rad})$	Arctangent of rel. amplitude attenuation
TNO	$n_o$	Refractive index of incident medium (dielectricum)
TNC	$n_c$	Refractive index of metal (complex)
TN	$n$	$\text{Re}(n_c)$
TK	$k$	$\text{Im}(n_c)$

Input Data for Program "CMOC"

The input data for the program CMOC are arranged on cards as illustrated below.

<u>Card</u>	<u>Col. 1-10</u>	<u>Col. 11-20</u>
1	TITLE	(Col. 1-80)
2	$n_0$	$\phi(\text{deg})$
3	$\psi(\text{deg})$	$\Delta(\text{deg})$

Cards 1-3 constitute one set. Three blank cards must follow the last set of data. The program together with a sample output is given below.

CMOC

```

PROGRAM CMOC (INPUT,OUTPUT)
C THIS PROGRAM IS INDEPENDENT OF ANGLE READINGS
C THIS PROGRAM COMPUTES N AND K FOR METALLIC REFLECTION
C FROM VALUES OF DELD,PSID,PHID AND TNO USING COMPLEX NU8BFRS
C
COMPLEX RHO,T2,S2,TNC,I
DIMENSION TITLE (8)
1 READ 76,TITLE
10 READ 3,TNO,PHID
3 FORMAT (2F10.0)
76 FORMAT (8A10)
20 PRINT 77,TITLE
77 FORMAT (1H0,8A10)
26 READ 3,PSID,DELD
36 IF (PSID) 100,100,2
40 2 PRINT 4
4 FORMAT (4HPHID,9X,3HTNO,8X,4HPSID,7X,4HDELD,10X,2HTN,10X,2HTK)
45 ALPHA=0.01745329252
46 PHI=PHID*ALPHA
47 PSI=PSID*ALPHA
50 DEL=DELD*ALPHA
52 I=CMPLX (0.0,1.0)
55 RHO=TAN(PHI)*CEXP(I*DEL)
73 S1=SIN(PHI)
75 T1=TAN(PHI)
77 T2=(1.0 + RHO)/((1.0 - RHO)*T1)
123 S2=T2/CSQRT(1.0 + T2*T2)
144 TNC=(TNO*S1)/S2
C
155 TN=REAL(TNC)
156 TK=AIMAG(TNC)
160 PRINT 6,PHID,TNO,PSID,DELD,TN,TK
6 FORMAT (F10.7,5F12.7)
177 GO TO 1
200 100 CONTINUE
201 END

```

AL	*** CMOC ***				
PHID	TNO	PSID	DELD	TN	TK
75.000000	1.000000	41.283000	114.773000	.810065	-5.469976

IV. FORTTRAN IV Computer Program "OZOM"

This program (One Zone Measurement) calculates the optical constants from ellipsometer readings of one zone taking into consideration the error introduced by the quarter wave plate.

The wave plate is characterized by the ratio,  $T_c$ , of the transmittance along its fast axis to the transmittance along its slow axis and the phase retardation,  $\Delta_c$ , along the axes giving  $\rho_c$ .

This calculation is based on the formulas given by McCrackin.<sup>8</sup>

All angles are measured positive counterclockwise from the plane of incidence. The components of the ellipsometer must be arranged in the order of light source, polarizer, quarter wave plate, reflecting surface, analyzer and light detector.

The value of  $\rho_c$  is calculated from readings of the polarizer and analyzer of two zones for one Q-value (quarter-wave circle reading), i.e., a two-zone measurement, (zone 1+3 or 2+4) which gives the angle-readings of the polarizer ( $P_1, P_2$ ) and of the analyzer ( $A_1, A_2$ ), is necessary to compute the error of the quarter-wave plate.\* Note that the one-zone-measurement has to be carried out with the same Q-value as the two-zone measurement.

Let  $P_i, A_i$  ( $i = 1, 2$ ) and  $Q$  be angles of two polarizer, analyzer and quarter-wave plate-settings, respectively, for extinction of the light. The quarter-wave plate is characterized by

\* Table I defines different zones.

$$\rho_c = T_c \exp(+i\Delta_c) \quad (36)$$

where  $T_c$  is the ratio of the transmittance along its fast axis to the transmittance along its slow axis:

$$T_c = \frac{1}{\sqrt{-\tan(P_1 - Q) \tan(P_2 - Q)}} \quad (37)$$

and the phase retardation  $\Delta_c$  along the axes

$$\tan\Delta_c = \frac{-B^2 - \tan(P_1 - Q) \tan(P_2 - Q)}{B} \quad (38)$$

where B is determined by

$$B = \frac{\tan A_1 [\tan(P_2 - Q) \tan Q - \tan(P_1 - Q) / \tan Q]}{2(\tan Q_1 - \tan A_2)} - \frac{\tan A_2 [\tan(P_1 - Q) \tan Q - \tan(P_2 - Q) / \tan Q]}{2(\tan A_1 - \tan A_2)} \quad (39)$$

The surface is characterized by the complex value  $\rho$  (Eq. (19))

$$\rho = \frac{r_p}{r_s} = \frac{|r_p|}{|r_s|} e^{i(\delta_p - \delta_s)} \quad (40)$$

The value of  $\rho$  is to be calculated from azimuth of P, A, Q.<sup>9</sup>

$$\rho = \frac{\tan A [\tan Q + \rho_c \tan(P - Q)]}{\rho_c \tan Q \tan(P - Q) - 1} \quad (40)$$

Having computed  $\rho$ , formulas of program "CMOC" are used: Application of Fresnel's Eqs. (28) and (29)

$$r_p = \frac{\tan(\phi - \phi'_c)}{\tan(\phi + \phi'_c)} = \frac{\frac{\sin(\phi - \phi'_c)}{\cos(\phi - \phi'_c)}}{\frac{\sin(\phi + \phi'_c)}{\cos(\phi + \phi'_c)}} \quad (28)$$

$$r_s = - \frac{\sin(\phi - \phi'_c)}{\sin(\phi + \phi'_c)} \quad (29)$$

leads to

$$\rho = - \frac{\cos(\phi + \phi'_c)}{\cos(\phi - \phi'_c)} \quad (30)$$

Use of Eqs. (5) through (8) give

$$\cos\phi'_c = \frac{\cos(\phi + \phi'_c) + \cos(\phi - \phi'_c)}{2 \cos\phi} \quad (31)$$

$$\cos\phi'_c = \frac{\cos(\phi - \phi'_c) - \cos(\phi + \phi'_c)}{2 \sin\phi} \quad (32)$$

which leads to

$$\tan\phi'_c = \frac{1 + \rho}{1 - \rho} \frac{1}{\tan\phi} \quad (33)$$

$\tan\phi'_c$  can be converted to  $\sin\phi'_c$  with

$$\sin\phi'_c = \frac{\tan\phi'_c}{\sqrt{1 + \tan^2\phi'_c}} \quad (34)$$

Then the (complex) refractive index is determined by

$$n_c = n - ik = \frac{n_o \sin\phi}{\sin\phi'_c} \quad (35)$$



Variables Used in This Program

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
TC	$T_c$	Ratio of transmittance along the fast axis to the transmittance along its slow axis of compensator
DEL C	$\Delta_c$	Phase retardance along the fast axis minus the phase retardance along the slow axis of compensator
RHOC	$\rho_c$	Complex number, characterizing the quarter-wave plate
RHO	$\rho$	Ratio of Reflection coefficients of p- and s-component (complex)
DELD	$\Delta$	Phase of ( $\rho$ )
PSID	$\psi$	Modulus of ( $\rho$ )
TNO	$n_o$	Refractive index of transparent incidence medium
TNC	$n_c$	Refractive index of reflecting surface (complex)
TN	$n$	$\text{Re}(n_c)$
TK	$k$	$\text{Im}(n_c)$
PD1	$P_1$ (deg)	Azimuth of P(Zone 1(2)) of the two-zone measurement
PD2	$P_2$ (deg)	Azimuth of P(Zone 3(4)) of the two-zone measurement
AD1	$A_1$ (deg)	Azimuth of A(Zone 1(2)) of the two-zone measurement
AD2	$A_2$ (deg)	Azimuth of A(Zone 3(4)) of the two-zone measurement
QD	$Q$ (deg)	Azimuth of Q (compensator)
AD	$A$	A-azimuth of a one-zone measurement (Zone 1 or 3 (2 or 4)) (deg)
PD	$P$	P-azimuth of a one-zone measurement (Zone 1 or 3 (2 or 4)) (deg)
PHID	$\phi$	Angle of incidence
WL	$\lambda_o$	Vacuum wavelength (Angstroms)

Input Format for Program "OZOM"

<u>Card</u>	<u>1-10</u>	<u>11-20</u>	<u>21-30</u>	<u>31-40</u>	<u>41-50</u>
1	} TITLE and Comments				
2					
3	$\bar{n}_0$	$\phi$	$\lambda_0$		
4	$P_1$	$P_2$	$A_1$	$A_2$	$Q$
5	$P$	$A$			

Cards 1-5 constitute one set. Three blank cards must follow the last set of data. All input data of angles should be in degrees. The program together with a sample output is given below.

OZOM

```

PROGRAM OZOM (INPUT,OUTPUT)
C THIS PROGRAM USES AZIMUTH READINGS
C THIS PROGRAM COMPUTES N AND K FOR METALLIC REFLECTION
C USING EXPERIMENTAL VALUES FROM ONE ZONE
C
COMPLEX PHO,T2,S2,TNC,I,RHOC
DIMENSION TITLE (8), RANGE (8)
ALPHA=0.01745329252
I=CMPLX (0.0,-1.0)
3 READ 76, TITLE,RANGE
6 76 FORMAT (8A10/8A10)
16 PRINT 77 , TITLF,RANGE
77 FORMAT (1H1, 8A10//8A10)
26 READ 3,TNO,PHID,WL
3 3 FORMAT (3F10.0)
40 IF (TNO) 100,100,4
42 4 CONTINUE
42 READ 81,PD1,PD2,AD1,AD2,QD
81* FORMAT (5F10.0)
60 READ 85,PD,AD
85 FORMAT (2F10.0)
70 P1=PD1*ALPHA
72 P2=PD2*ALPHA
73 A1=AD1*ALPHA
75 A2=AD2*ALPHA
76 Q=QD*ALPHA
100 A=AD*ALPHA
101 P=PD*ALPHA
C
103 B=(TAN(A1))*(TAN(P2-Q)*TAN(Q)-TAN(P1-Q)/TAN(Q))-TAN(A2)*(-Q)*(TAN(P1
CTAN(Q)-TAN(P2-Q)/TAN(Q)))/2.0/(TAN(A1)-TAN(A2))
135 DELC=ATAN2(SORT(-B*B-TAN(P1-Q)*TAN(P2-Q)),B)
155 TC=1.0/SORT(-TAN(P1-Q)*TAN(P2-Q))
172 RHOC=TC*CEXP(+I*DELC)
C
207 PHO =(TAN(A)*(-Q)*(TAN(Q)+RHOC *TAN(P-Q)))/(RHOC *TAN(Q)*TAN(P-Q)-
250 PSID=ATAN(CABS(RHO ))/ALPHA
254 DELD=ATAN2(AIMAG(RHO ),REAL(RHO ))/ALPHA
263 PHI=PHID*ALPHA
C
265 S1=SIN(PHI)
267 T1=TAN(PHI)
271 T2=(1.0 + RHO)/((1.0 - RHO)*T1)
315 S2=T2/CSQRT(1.0 + T2*T2)
336 TNC=(TNO*S1)/S2
347 TN=REAL(TNC)
350 TK=AIMAG(TNC)
352 DELC=DELC/ALPHA
C
353 PRINT 10, PHID,TNO,WL
10 FORMAT (1H0,/7HPHID = ,F5.2,10X,7HTNO = ,F7.3,10X,13HWAVELENG
C ,F5.0,10H ANGSTROM //)
365 PRINT 11,PD1,AD1,PD2,AD2,QD
11 FORMAT (1HC,/ 6HPPD1 = ,F6.2,10X,7HAD1 = ,F6.2,/,6HPPD2 = ,F6.
C10X,7HAD2 = ,F6.2,/,6HQD = ,F6.2)
403 PRINT 8,TC,DELC
8 FORMAT (1H0,/6HTC = ,F8.4,8X,7HDELC = ,F8.4//)

```

```
413      PRINT 12,PD,AD
      12 FORMAT(1HO,/6HPD = ,F6.2,10X,7HAD = ,F6.2//)
423      PRINT 13,PSID,DELD,TN,TK
      13 FORMAT (1HO,/6HPSID = ,F8.4,8X,7HDELD = ,F8.4,/,6HTN = ,F8.4,
      C 8X,7HTK = ,F8.4)
      C
437      GO TO 1
440      100 CONTINUE
441      END
```

Sample output, program OZOM

MGF2 ON CR (3.48) \*\*\* OZOM \*\*\*

ZONE A3 (A1/A3)

PHID = 75.00                      TNO =    1.000                      WAVELENGTH = 5461 ANGSTROM

PD1 = 18.87                      AD1 = 142.47

PD2 = 108.71                     AD2 = 38.42

OD = 45.00

TC = 1.0037                      DFLLC = 91.1642

PD = 108.71                      AD = 38.42

PSID = 37.9756                    DELD = 52.4131

TN = .6438                        TK = -1.4867

V. FORTAN IV Computer Program "FILM"

This program finds the thickness and (complex) refractive index of a single film (absorbing or non-absorbing) on any substrate (absorbing or non-absorbing)\*. It does so by systematically combining all prescribed values of film thickness  $L$  and refractive index  $n_f - ik_f$  and calculating the polarizer- and analyzer-azimuths ( $P_c, A_c$ ), for each combination. Wherever a particular combination of  $L$ ,  $n_f$  and  $k_f$  yields agreement with the experimentally determined readings of polarizer  $P_m$  and analyzer  $A_m$  within a specified error  $\epsilon_p$  and  $\epsilon_A$ , this combination appears in the output as a solution.

The formalism assumes a planar substrate covered with a planar-parallel, homogeneous, isotropic film (Fig. 1). Drude's basic equation<sup>10</sup>

$$\rho = \frac{(r_{1p} + r_{2p} e^{-iD}) (1 + r_{1s} r_{2s} e^{-iD})}{(r_{1s} + r_{2s} e^{-iD}) (1 + r_{1p} r_{2p} e^{-iD})} = \tan \psi e^{i\Delta} \quad (36)$$

can be solved to give calculated values of  $\Delta$  and  $\psi$  by use of the following equations:\*\*

$$r_{1s} = \frac{E_{1s}}{E_s} = \frac{n_o \cos \phi - n_{cf} \cos \phi_{cf}}{n_o \cos \phi + n_{cf} \cos \phi_{cf}} \quad (37)$$

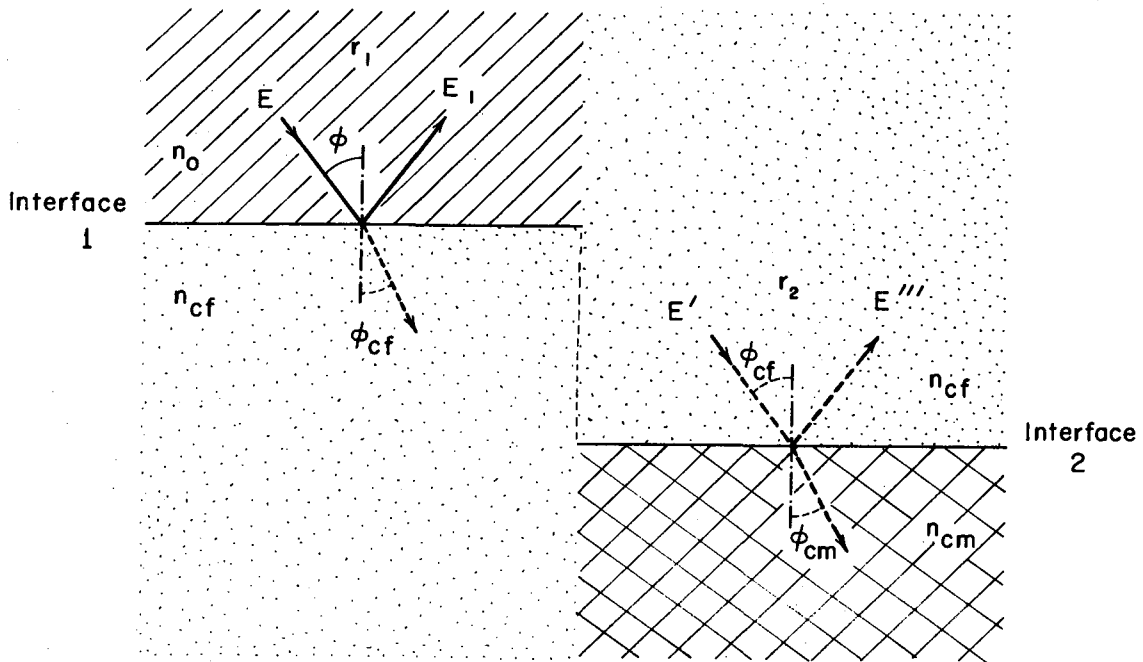
$$r_{1p} = \frac{E_{1p}}{E_p} = \frac{n_{cf} \cos \phi - n_o \cos \phi_{cf}}{n_{cf} \cos \phi + n_o \cos \phi_{cf}} \quad (38)$$

$$r_{2s} = \frac{E'''_s}{E'_s} = \frac{n_{cf} \cos \phi_{cf} - n_{cm} \cos \phi_{cm}}{n_{cf} \cos \phi_{cf} + n_{cm} \cos \phi_{cm}} \quad (39)$$

$$r_{2p} = \frac{E'''_p}{E'_p} = \frac{n_{cm} \cos \phi_{cf} - n_{cf} \cos \phi_{cm}}{n_{cm} \cos \phi_{cf} + n_{cf} \cos \phi_{cm}} \quad (40)$$

\* Program "LAYER" (Chapter VIII) is similar to this program.

\*\* See Fig. 1.



XBL719-4365

Fig. 1. Reflection coefficient  $r_1$  and  $r_2$  at both interfaces of a film-covered surface. Designation of refractive indices and electric fields. All the angles of propagation except  $\phi$  are complex (indicated by dotted circles and lines) and cannot be interpreted geometrically.

with

$$\cos\phi_{cf} = \sqrt{1 - \frac{n_o^2 \sin^2\phi}{n_{cf}^2}} \quad (41)$$

$$\cos\phi_{cm} = \sqrt{1 - \frac{n_{cf}^2 \sin^2\phi_{cf}}{n_{cm}^2}} \quad (42)$$

and

$$D = \frac{4\pi L}{\lambda_o} n_{cf} \cos\phi_{cf} \quad (43)$$

$\Delta$  and  $\psi$  (defined in Eqs. (21) and (22)) are given by:

$$\Delta = \tan^{-1} \frac{\text{Im}(\rho)}{\text{Re}(\rho)} \quad (44)$$

$$\psi = \tan^{-1} (|\rho|) \quad (45)$$

The calculated polarizer and analyzer azimuths  $P_c$  and  $A_c$  are obtained according to Table I.

$$P_c = (270 - \Delta)/2$$

$$A_c = \psi$$

This program is valid for zone A-3:

range of polarizer transmission azimuth	90-135°
range of analyzer transmission azimuth	0-90°
compensator circle realing	45°

Using different zones, one has to change the conversion from  $P_c, A_c, Q$  to  $\Delta$  and  $\psi$  according to Table I.



Variables Used in Program FILM

a. Real Quantities

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
AC	$A_c$	Calculated azimuth angle of analyzer (deg)
AM	$A_m$	Measured azimuth angle of analyzer (deg)
DELC	$\Delta(\text{calculated})$	Relative phase change (deg)
DTN	$\delta n_f$	Iteration increment of film refractive index $n_f$
DTNK	$\delta k_f$	Iteration increment of index of extinction of film
DT	$\delta L$	Iteration increment of film thickness L
EAM	$\epsilon_A$	Specified experimental error of A (deg)
EPM	$\epsilon_P$	Specified experimental error of P (deg)
PHI1	$\phi(\text{degrees})$	Angle of incidence
PHI	$\phi(\text{radians})$	Angle of incidence
PC	$P_c$	Calculated azimuth angle of polarizer (deg)
PM	$P_m$	Measured azimuth angle of polarizer (deg)
PSIC	$\psi(\text{calculated})$	Arctangent of relative amplitude attenuation (deg)
Q	Q	Measured azimuth angle of compensation (deg)
TN1	$n_o$	Refractive index of incident medium
TNS	$n_m$	Refractive index of substrate
TNKS	$k_m$	Index of extinction of substrate
TNI	$n_{fi}$	Lower limit of interaction span of film index $n_f$
TN	$n_f$	Refractive index of film
TNM	$n_{fm}$	Upper limit of iteration span of film index $n_f$
TNKI	$k_{fi}$	Lower limit of iteration span of $k_f$ of film
TNK	$k_f$	Index of extinction of film
TNKM	$k_{fm}$	Upper limit of iteration span of $k_f$ of film

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
TI	$L_i$	Lower limit of iteration span for film thickness L
T	L	Film thickness (units as for $\lambda_o$ )
TM	$L_m$	Upper limit of iteration span of film thickness
WL	$\lambda_o$	Vacuum wavelength (Angstroms)

b. Complex Qualities

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
CPHI2	$\cos \phi'$	Complex cosine of complex angle of refraction in film
CPHI3	$\cos \phi'_m$	Complex cosine of complex angle of refraction in substrate
D	$d$	Complex optical path length
R1S	$r_{1s}$	Fresnel reflection coefficient at film-air (or incident medium) interface. (For polarization normal to plane of incidence)
R1P	$r_{1p}$	Fresnel reflection coefficient at film-air (or incident medium) interface. (For polarization parallel to plane of incidence)
R2S	$r_{2s}$	Fresnel reflection coefficient at metal-film interface (normal polarization)
R2P	$r_{2p}$	Fresnel reflection coefficient at metal-film interface (parallel polarization)
RS	$r_s$	Overall reflection coefficient for polarization normal to plane of incidence
RP	$r_p$	Overall reflection coefficient for polarization parallel to plane of incidence
RHO	$\rho = r_p / r_s = \tan \psi e^{i\Delta}$	
TN3	$n_m - ik_m$	Complex refractive index of substrate
TN2	$n_f - ik_f$	Complex refractive index of film

Input Format for Program FILM

Card	Columns					
	<u>1-10</u>	<u>11-20</u>	<u>21-30</u>	<u>31-40</u>	<u>41-50</u>	<u>51-70</u>
1 } 2 }	Title and comments (up to 80 columns each)					
3	$n_o$	$\lambda_o$	$n_m$	$k_m$		
4	$n_{fi}$ (initial)	$\delta n_f$ (increment)	$n_{fm}$ (final)	$k_{fi}$ (initial)	$\delta k_f$ (increment)	$k_{fm}$ (final)
5	$L_i$ (initial)	$\delta L$ (increment)	$L_m$ (final)			
6	$\phi$	$P_m$	$A_m$	$\epsilon_P$	$\epsilon_A$	Q

These six cards constitute a set. Any number of sets may follow. Three blank cards must follow the last set of data. Cards 1 and 2 of each set may contain any comments (or none at all) as desired. Their contents appear printed verbatim at the head of the output.

This program can be used to calculate theoretical values of  $P_c$  and  $A_c$  with changes in film thickness or with different film constants, by punching numbers greater than (or equal to) 90 for  $\epsilon_A$  and a number greater than (or equal to) 180 for  $\epsilon_P$ . Then the entries for  $P_m$  and  $A_m$  should be blank.

The program, together with a sample of output, is reproduced below.

FILM

```

PROGRAM FILM (INPUT,OUTPUT)
C THIS PROGRAM USES AZIMUTH READINGS
C THIS PROGRAM CALCULATES THE THICKNESS AND COMPLEX REFRACTIVE
C INDEX OF A SINGLE ABSORBING FILM ON AN ABSORBING SUBSTRATE
C USING ELLIPSOMETER READINGS OF ZONE A3
C COMPLEX TN2, TN3, CPHI2, CPHI3, R1S, R1P, R2S, R2P, D, RS, RP
C DIMENSION TITLE (8), RANGE (8)
1 READ 2, TITLE,RANGE
2 FORMAT (8A10/8A10)
12 3 PRINT 4, TITLE,RANGE
4 FORMAT (1H1, 8A10//8A10)
22 5 READ 9, TN1,WL,TNS,TNKS
36 IF (TN1) 3000, 3000, 6
40 6 READ 10, TNI,DTN,TNM,TNKI,DTNK,TNKM
60 7 READ 11, TI,DT,TM
72 8 READ 12,PHI1,PM,AM,EPM,EAM,Q
9 FORMAT (4F10.0)
10 FORMAT (6F10.0)
11 FORMAT (3F10.0)
12 FORMAT (6F10.0)
13 FORMAT (1HC,/6H PHI = ,F5.2,10X,4HN = ,F7.4, 10X, 13HWAVELENGTH
C F5.0, 11H ANGSTROMS//33H REFRACTIVE INDEX OF SUBSTRATE = ,
C 2X, 4H- I, F7.4)
14 FORMAT (1HC, 27H REFRACTIVE INDEX OF FILM = , F7.4, 2X,
C 4H- I, F7.4//18H FILM THICKNESS = , F7.2, 10H ANGSTROMS,
C //8H PSIC = , F10.5, 10X, 7H DELC = , F10.5,
C //8H PSIM = , F10.5, 10X, 7H DELM = , F10.5)
141 FORMAT (1HC, 5HPC = ,F10.5,10X,5HAC = ,F10.5,10X,4HQ = .F5.2)
15 FORMAT (1HC, 5HPM = ,F10.5,10X,, 5HAM = ,F10.5//33H NO SOLUT
C WITHIN GIVEN LIMITS)
151 FORMAT (1HC, 5HPM = ,F10.5,10X,5HAM = ,F10.5,10X,4HQ = ,F6.2)
112 IF (PM) 16,16,17
114 16 DELM=0.
115 PSIM=0.
116 GO TO 18
116 17 DELM=270.-2.*PM
121 PSIM=AM
123 18 FDELM=2.0*EPM
125 EPSIM=EAM
126 M = 1
127 PHI = 0.01745329252*PHI1
132 CP = COS(PHI)
133 SP = SIN(PHI)
135 TN3 = CMPLX(TNS,-TNKS)
141 CPHI3 = CSORT(1.0 - TN1**2*SP**2/(TN3**2))
163 TN = TNI
165 20 TNK = TNKI
167 30 T = TI
171 100 TN2 = CMPLX(TN,-TNK)
174 CPHI2 = CSORT(1.0 - TN1**2*SP**2/(TN2**2))
217 R1S = (TN1*CP - TN2*CPHI2)/(TN1*CP + TN2*CPHI2)
251 R1P = -(TN1*CPHI2 - TN2*CP)/(TN1*CPHI2 + TN2*CP)
302 R2S = (TN2*CPHI2 - TN3*CPHI3)/(TN2*CPHI2 + TN3*CPHI3)
341 R2P = -(TN2*CPHI3 - TN3*CPHI2)/(TN2*CPHI3 + TN3*CPHI2)
377 D = (0.0,1.0)*(4.0*3.1415927*T/WL)*TN2*CPHI2
415 RS = (R1S + R2S*CEXP(-D))/(1.0 + R1S*R2S*CEXP(-D))
454 RP = (R1P + R2P*CEXP(-D))/(1.0 + R1P*R2P*CEXP(-D))

```

```
513      RHO = RP/PS
523      PSIC = ATAN(CABS(RHO))/0.01745329252
527      DELC = ATAN2(AIMAG(RHO), REAL(RHO))/0.01745329252
536      IF (DELC) 140,140,150
540      140 DELC = DELC + 360.00
542      150 IF (FPSIM - ABS(PSIC - PSIM)) 400, 200, 200
547      200 IF (EDELN - ABS(DELC - DELM)) 400, 300, 300
554      300 PRINT 13, PH11,TN1,WL,TNS,TNKS
572      PRINT 14, TN,TNK,T,PSIC,DELC,PSIM,DELM
614      PRINT 151,PM,AM,0
626      PC=(270.0-DELC)/2.0
631      AC=      PSIC
632      PRINT 141,PC,AC,0
644      M = 2
645      400 IF(TM -T) 600,600,500
650      500 T = T + DT
652      GO TO 100
653      600 IF(TNKM - TNK) 800,800,700
656      700 TNK = TNK + DTNK
660      GO TO 30
661      800 IF(TNM - TN) 1000,1000,900
664      900 TN = TN + DTN
666      GO TO 20
667      1000 GO TO (2000, 1) M
675      2000 PRINT 13, PH11,TN1,WL,TNS,TNKS
713      PRINT 15,PM,AM
723      GO TO 1
724      3000 CONTINUE
725      END
```

Sample output, program FILM

MGF2 ON CR \*\*\* FILM \*\*\*  
ZONE A3 (AZIMUTH)

PHI = 75.00	N = 1.0000	WAVELENGTH = 5461	ANGSTROMS
REFRACTIVE INDEX OF SUBSTRATE = .9300 - I 2.3900			
REFRACTIVE INDEX OF FILM = 1.3800 - I-0.0000			
FILM THICKNESS = 400.00 ANGSTROMS			
PSIC = 41.11701	DELC = 55.78266		
PSIM = 41.11000	DELM = 55.80000		
PM = 107.10000	AM = 41.11000	Q = 45.00	
PC = 107.10867	AC = 41.11701	Q = 45.00	

VI. FORTRAN IV Computer Program "A3PLOT"

This program calculates theoretical quantities of polarizer and analyzer values of the ellipsometer with changes in film thickness.\* Depending on the code number M (see below), results are given as curves or tables.

The equation and variables used in this program are similar to those used in program "FILM".

As program "FILM" this program is only valid for zone A-3 (see Table I):

range of polarizer transmission azimuth	90-135°
range of analyzer transmission azimuth	0-90°
compensator circle realing	45°

---

\*This program makes use of program "FPLOT" (see Chapter IX).

Input Format for Program A3PLOT

Card	Columns					
	<u>1-9</u>	<u>10-19</u>	<u>20-29</u>	<u>30-39</u>	<u>40-49</u>	<u>50-59</u>
1 } 2 }	Title and comments (up to 80 columns)					
3	$n_o$	$\lambda_o$	$n_m$	$k_m$		
4	$n_{fi}$ (initial)	$\delta n_f$ (increment)	$n_{fm}$ (final)	$k_{fi}$ (initial)	$\delta k_f$ (increment)	$k_{fm}$ (final)
5	$L_i$	$\delta L$	$L_m$ (limited to 200 points)			
6	$\phi$	M				

These six cards constitute a set. Any number of sets may follow. In each set, the values of the optical constants of the film may be varied. Three blank cards must follow the last set of cards.

M is the code number. The integer used for M determines how the results will be presented.



M                    Format of Results

- 0     Results will be tabulated and given as three curves
- a)  $\psi$  vs  $\Delta$  curve with thickness as parameter
  - b)  $A_c$  vs film thickness
  - c)  $P_c$  vs film thickness
- 1     Results will be tabulated and only the  $\psi$  vs  $\Delta$  curve is plotted
- 2     Results will be tabulated and two curves will be plotted
- a)  $A_c$  vs film thickness
  - b)  $P_c$  vs film thickness
- 3     Results will be given only as three curves
- a)  $\psi$  vs  $\Delta$
  - b)  $A_c$  vs film thickness
  - c)  $P_c$  vs film thickness
- 4     Output has only the  $\psi$  vs  $\Delta$  curve
- 5     Two curves will be given
- a)  $A_c$  vs film thickness
  - b)  $P_c$  vs film thickness

The maximum number of data points for L (thickness) is 200. If the  $\psi$  vs thickness and  $\Delta$  vs thickness curves are to be plotted, the maximum number is reduced to 101. The program "FILM" should be used instead, if only tabulated results are wanted.

This program "A3PLOT" has to utilize the subroutines "PRNPLT" and "PLSCAL" written by M. S. Itzkowitz to do the plotting of the curves. These two subroutines are library subroutines and they are stored in the computer (control data 7600 system) at Lawrence Berkeley Laboratory.

If the data are plotted, the scale of the thickness (x-axes) is divided into 100 parts from 0-10,000 A (increment (100 A), whereas the y-axes (P or A scale) is divided in 50 parts from 0-360° for P (increment 7.2°) and 0-180° (increment 3.6°) for A. The scales can be changed by using different "CALL PRNPLT"-cards. Cards numbers 670, 672, 774, 1052, 1464 of the program have the following form:

```
CALL PRNPLT(XPLOT, YPLOT, XMAX, XINCR, YMAX, YINCR, ISX, ISY, NPOINT)
```

with

- XMAX determines the upper limit of the x-axes (thickness)
- XINCR determines the increment of the x-values (increments of thickness)
- YMAX determines the upper limit of the y-axes (A, P-values)
- YINCR determines the increment of the y-values (increments of P, A-values).
- ISX=0 means scaling of x-axes is done by programmer
- ISX=1 means scaling of x-axes is done by computer
- ISY=0 means scaling of y-axes is done by programmer
- ISY=1 means scaling of y-axes is done by computer

In any case, the x-axes is divided into 100 parts; the y-axes into 50 parts.

A reproduction of the main program and the two subroutines is given below.

A3PLOT

```

PROGRAM A3PLOT (INPUT,OUTPUT)
C THIS PROGRAM USES AZIMUTH READINGS
C THIS PROGRAM CALCULATES AC AND PC FROM FILM THICKNESS
C IT ALSO PLOTS AC VERSUS PC CURVE WITH FILM THICKNESS AS PA
C AND AC VERSUS FILM THICKNESS, PC VERSUS FILM THICKNESS.
C ZONE A3
C COMPLEX TN2, TN3, CPHI2, CPHI3, R1S, R1P, R2S, R2P, D, RS, RP,
C DIMENSION TITLE (8), RANGE (8)
C DIMENSION XPLOT(200), YPLOT(200), ZPLOT(200)
1 PFAD 2, TITLE,RANGE
2 FORMAT (8A10/8A10)
12 3 PPRINT 4, TITLE,RANGE
4 FORMAT (1H1, 8A10//8A10)
22 5 READ 9, TN1,WL,TNS,TNKS
36 IF (TN1) 3000, 3000, 6
40 6 READ 10, TN1,DTN,TNM,TNKI,DTNK,TNKM
60 7 READ 11, TI,DT,TM
72 IF (TI.NE.C.C) TD=TM-TI
75 8 READ 12, PHI1,M
9 FORMAT (F9.0, 3F10.0)
10 FORMAT (F9.0, 5F10.0)
11 FORMAT (F9.0, 2F10.0)
12 FORMAT (F9.0, I1 )
13 FORMAT (1H0,/6H PHI = ,F5.2,10X,4HN = ,F7.4, 10X, 13HWAVELENGTH
C F5.0, 11H ANGSTROMS//33H REFRACTIVE INDEX OF SUBSTRATE = , F
C 2X, 4H- I, F7.4)
14 FORMAT (1H0, 27H REFRACTIVE INDEX OF FILM = , F7.4, 2X,
C 4H- I, F7.4//18H FILM THICKNESS = , F8.2, 10H ANGSTROMS,
C //8H AC = , F10.5, 10X, 7H PC = , F10.5)
15 FORMAT (1H1)
16 FORMAT (22H PSIC VERSUS DELC CURVE)
17 FORMAT (6H PHI = ,F5.2,10X,4HN = ,F7.4,10X,13HWAVELENGTH = ,
C F5.0,4H A ,5X,13HNM - IKM = ,F7.4,2X,4H- I,F7.4)
18 FORMAT (13HNF - IKF = ,F7.4,2X,4H- I,F7.4)
19 FORMAT (26H PC VERSUS FILM THICKNESS)
21 FORMAT (26H AC VERSUS FILM THICKNESS)
105 PHI = 0.01745329252*PHI1
107 CP = COS(PHI)
111 SP = SIN(PHI)
113 TN3 = CMPLX(TNS,-TNKS)
117 CPHI3 = CSQRT(1.0 - TN1**2*SP**2/(TN3**2))
141 TN = TN1
143 20 TNK = TNKI
145 30 T = TI
146 NPOINT = 1
150 100 TN2 = CMPLX(TN,-TNK)
153 CPHI2 = CSQRT(1.0 - TN1**2*SP**2/(TN2**2))
176 R1S = (TN1*CP - TN2*CPHI2)/(TN1*CP + TN2*CPHI2)
230 R1P = -(TN1*CPHI2 - TN2*CP)/(TN1*CPHI2 + TN2*CP)
261 R2S = (TN2*CPHI2 - TN3*CPHI3)/(TN2*CPHI2 + TN3*CPHI3)
320 R2P = -(TN2*CPHI3 - TN3*CPHI2)/(TN2*CPHI3 + TN3*CPHI2)
356 D = (0.0,1.0)*(4.0*3.1415927*T/WL)*TN2*CPHI2
374 RS = (R1S + R2S*CEXP(-D))/(1.0 + R1S*R2S*CEXP(-D))
433 RP = (R1P + R2P*CEXP(-D))/(1.0 + R1P*R2P*CEXP(-D))
472 RHO = RP/RS
502 PSIC = ATAN(CABS(RHO))/0.01745329252
506 DELC = ATAN2(AIMAG(RHO), REAL(RHO))/0.01745329252

```

```

515      IF (DELCL) 140,140,150
517      140 DELC = DELC + 360.00
521      150 PC=(270.-DELC)/2.
524      AC=PSIC
525      IF(M.GT.2) GO TO 300
531      PRINT 13, PH11,TN1,WL,TNS,TNKS
546      PRINT 14, TN,TNK,T,AC,PC
565      300 XPLCT(NPOINT) = PC
566      YPLOT(NPOINT) = AC
570      IF(M.EQ.1.OR.M.EQ.4) GO TO 400
600      IF(TI.EQ.0.0) GO TO 3500
601      ZPLCT(NPOINT) = T - TD
604      GO TO 400
604      3500 ZPLCT(NPOINT) = T
606      400 NPCINT = NPOINT + 1
610      IF(TM -T) 600,600,500
613      500 T = T + DT
615      GO TO 100
616      600 NPCINT = NPOINT - 1
620      IF(M.EQ.2.OR.M.EQ.5) GO TO 1500
627      PRINT 15
632      PRINT 16
636      PRINT 17, PH11,TN1,WL,TNS,TNKS
654      PRINT 18, TN,TNK
665      XPLCT(NPOINT) = DELC
666      YPLOT(NPOINT) = PSIC
670      CALL PRNPLT(XPLOT,YPLOT,360.,5.0,90.,2.0,0.,0.,NPOINT)
702      XPLCT(NPOINT) = PC
703      YPLOT(NPOINT) = AC
705      IF(M.EQ.1.OR.M.EQ.4) GO TO 1100
715      1500 PRINT 15
721      PRINT 21
725      PRINT 17, PH11,TN1,WL,TNS,TNKS
743      PRINT 18, TN,TNK
753      IF(TI.EQ.0.0) GO TO 3100
754      PRINT 3300, TD
762      3300 FORMAT (5HADD ,F8.2,17HTO SCALE READINGS)
773      CALL PRNPLT(ZPLOT,YPLOT,TM,10.,100.,2.0 ,0,0,NPOINT)
774      GO TO 3400
1005      3100 CALL PRNPLT(ZPLOT,YPLOT,TM,10.,100.,2.0 ,0,0,NPOINT)
1011      3400 PRINT 15
1015      PRINT 19
1033      PRINT 17, PH11,TN1,WL,TNS,TNKS
1043      PRINT 18, TN,TNK
1044      IF(TI.EQ.0.0) GO TO 3200
1052      PRINT 3300, TD
1063      CALL PRNPLT(ZPLOT,XPLOT,TM,10.,135.,1.0,0,0,NPOINT)
1064      GO TO 1100
1075      3200 CALL PRNPLT(ZPLOT,XPLOT,TM,10.,135.,1.0,0,0,NPOINT)
1100      IF(TNKM - TNK) 800,800,700
1102      700 TNK = TNK + DTNK
1103      GO TO 30
1106      800 IF(TNM - TN) 1000,1000,900
1110      900 TN = TN + DTN
1111      GO TO 20
1112      1000 GO TO 1
1113      3000 CONTINUE
1113      END

```

PRNPLT

```
      SUBROUTINE PRNPLT(X,Y,XMAX,XINCR,YMAX,YINCR,ISX,ISY,NPTS)
C     PRINTER PLOT ROUTINE      M.S.ITZKOWITZ      MAY,1967
C
C     PLOTS THE *NPTS* POINTS GIVEN BY *X(I),Y(I)* ON A 51 X 101 GRID
C     USING A TOTAL OF 56 LINES ON THE PRINTER
C     IF *ISX* OR *ISY* ARE NON-ZERO, THE CORRESPONDING MAXIMUM AND
C     INCREMENTAL STEP SIZE ARE COMPUTED
C     IF EITHER INCREMENTAL STEP SIZE IS ZERO, THE PROGRAM EXITS
C     NEITHER OF THE INPUT ARRAYS ARE DESTROYED. IF SCALING IS DONE
C     THE CORRESPONDING NEW VALUES OF MAXIMUM AND STEP SIZE ARE RETU
C
      DIMENSION X(NPTS),Y(NPTS),IGRID(105),XAXIS(11)
C
      INTEGER BLANK,DOT,STAR,IGRID,PLUS
      DATA BLANK,DOT,STAR,PLUS / 1H ,1H.,1H*,1H+ /
C
901    FORMAT(14X,105A1)
902    FORMAT(1XF10.3,2X,1H+,105A1,1H+)
903    FORMAT(15X,103(1H.))
904    FORMAT(7X,11(F10.0),2H (,14,5H PTS) )
905    FORMAT(16X,11(1H+,9X))
9800   FORMAT(46H1SCALING ERROR IN PRNPLT, EXECUTION TERMINATED )
C
      IF (ISX.NE.0) CALL PLSCAL(X,XMAX,XINCR,NPTS,100)
      IF (ISY.NE.0) CALL PLSCAL(Y,YMAX,YINCR,NPTS,50)
      IF (XINCR.EQ.0..OR.YINCR.EQ.0.) GO TO 800
      YAXMIN=0.01*YINCR
      XAXMIN=0.01*XINCR
      IZERO=YMAX/YINCR+1.5
      JZERO=103.5-XMAX/XINCR
      IF (JZERO.GT.103..OR.JZERO.LT.4) JZERO=2
      PRINT 905
      PRINT 903
      DO 10 I=1,51
103    IF ( I.NE.IZERO) GO TO 16
104    DO 14 J=1,105
112  14  IGRID(J)=PLUS
113    GO TO 15
117  16  DO 11 J=1,105
125  11  IGRID(J)=BLANK
132  15  IGRID(JZERO)=PLUS
133    IGRID(104)=DOT
136    IGRID(2)=DOT
137    DO 12 K=1,NPTS
140    ITEST =(YMAX-Y(K))/YINCR+1.5
144    IF (ITEST .NE.1) GO TO 12
146    J=103.5-(XMAX-X(K))/XINCR
152    IF (J.GT.103) J=105
156    IF (J.LT.3) J=1
162    IGRID(J)=STAR
164  12  CONTINUE
167    IF (MOD(I,10).EQ.1) GO TO 13
174    PRINT 901,IGRID
201    GO TO 10
205  13  YAXIS=YMAX-(I-1)*YINCR
211    IF (ABS(YAXIS).LT.YAXMIN) YAXIS=0.
216    PRINT 902,YAXIS,(IGRID(J),J=1,105)
```

```
232 10  CONTINUE
234      PRINT 903
240      PRINT 905
247      DO 20 M=1,11
254      XAXIS(M)=XMAX-XINCR*(FLOAT(11-M))*10.0
257      IF (ABS(XAXIS(M)).LT.XAXMIN) XAXIS(M)=0.
266 20  CONTINUE
270      PRINT 904,XAXIS,NPTS
300      RETURN
301 800  PRINT 9800
305      CALL EXIT
306      END
```

PLSCAL

SUBROUTINE PLSCAL(V,VMAX,VINCR,NPTS,NDIVIS)

```
C
C SCALING PROGRAM FOR USE WITH PRNPLT M.S.ITZKOWITZ MAY,1967
C THIS VERSION ADJUSTS THE FULL SCALE TO 2.5,5.0, OR 10. TIMES 10**
C AND ADJUSTS THE MAXIMUM POINT TO AN INTEGER MULTIPLE OF 5*VINCR
C
C DIMENSION V(NPTS)
C
10 VMIN=V(1)
11 VMAX=V(1)
12 DO 10 I=1,NPTS
16 IF(V(I).LT.VMIN) VMIN=V(I)
16 IF(V(I).GT.VMAX) VMAX=V(I)
23 QRANGE=VMAX-VMIN
25 10 CONTINUE
27 IF(QRANGE.EQ.0.) GO TO 8000
30 QRANGE=0.4342944*ALOG(QRANGE)
32 IF(QRANGE)20,20,30
37 30 IRANGE=QRANGE
41 GO TO 40
42 20 IRANGE=-QRANGE
43 IRANGE=-IRANGE-1
46 40 QRANGE=QRANGE-FLOAT(IRANGE)
50 RANGE=10.**QRANGE
C
C RANGE IS BETWEEN 1.0 AND 10.0
C
53 43 IF(RANGE.GT.2.5) GO TO 41
57 RANGE=2.5
57 GO TO 50
60 41 IF(RANGE.GT.5.0) GO TO 42
64 RANGE=5.0
64 GO TO 50
65 42 RANGE=10.0
67 50 TRANGE=RANGE*(10.**IRANGE)
C
C TRANGE IS NOW 2.5,5.0, OR 10.0 TIMES A POWER OF TEN
C
73 VINCF=TRANGE/FLOAT(NDIVIS)
75 IF(VMAX)51,51,52
77 52 IMAX=VMAX/(5.0*VINCR)
101 XMAX=5.0*VINCR*FLOAT(IMAX+1)
104 GO TO 53
105 51 IMAX=-VMAX/(5.0*VINCR)
110 XMAX=5.0*VINCR*FLOAT(-IMAX+1)
113 53 IF(VMIN.GT.XMAX-TRANGE) GO TO 100
120 RANGE=RANGE*2.0
121 IF(RANGE-10.) 43,43,54
124 54 RANGE=RANGE/10.
126 IRANGE=IRANGE+1
127 GO TO 43
130 100 VMAX=XMAX
131 VMIN=XMAX-TRANGE
133 RETURN
134 8000 PRINT 9800
134 9800 FORMAT(45H1PLSCAL CALLED TO SCALE ARRAY WITH ZERO RANGE)
143 CALL EXIT
144 END
```

GOLD ON CHROMIUM

\*\*\* A3PLOT \*\*\*

PC AND AC (OPT.5) VERSUS FILM THICKNESS (0 - 1000 Å)

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
FILM THICKNESS = -0.00 ÅNGSTROMS  
AC = 19.73136            PC = 88.28943

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
FILM THICKNESS = 50.00 ÅNGSTROMS  
AC = 26.29669            PC = 90.91716

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
FILM THICKNESS = 100.00 ÅNGSTROMS  
AC = 30.96695            PC = 92.84166

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
FILM THICKNESS = 150.00 ÅNGSTROMS  
AC = 34.20930            PC = 94.34942

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
FILM THICKNESS = 200.00 ÅNGSTROMS  
AC = 36.44506            PC = 95.54335

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461 ÅNGSTROMS



REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 250.00 ANGSTROMS

AC = 37.98865 PC = 96.48510

PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 ANGSTROMS

REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 300.00 ANGSTROMS

AC = 39.05905 PC = 97.22308

PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 ANGSTROMS

REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 350.00 ANGSTROMS

AC = 39.80513 PC = 97.79789

PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 ANGSTROMS

REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 400.00 ANGSTROMS

AC = 40.32759 PC = 98.24346

PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 ANGSTROMS

REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 450.00 ANGSTROMS

AC = 40.69481 PC = 98.58760

PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 ANGSTROMS

REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000

REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

FILM THICKNESS = 500.00 ANGSTROMS

AC = 40.95360 PC = 98.85264

-45-

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
 FILM THICKNESS = 550.00 ANGSTROMS  
 AC = 41.13624            PC = 99.05631

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
 FILM THICKNESS = 600.00 ANGSTROMS  
 AC = 41.26518            PC = 99.21254

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
 FILM THICKNESS = 650.00 ANGSTROMS  
 AC = 41.35616            PC = 99.33217

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
 FILM THICKNESS = 700.00 ANGSTROMS  
 AC = 41.42025            PC = 99.42365

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500  
 FILM THICKNESS = 750.00 ANGSTROMS  
 AC = 41.46528            PC = 99.49350

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
 REFRACTIVE INDEX OF SUBSTRATE = 2.9900 - I 2.3000  
 REFRACTIVE INDEX OF FILM = .3500 - I 2.3500

AC VERSUS FILM THICKNESS

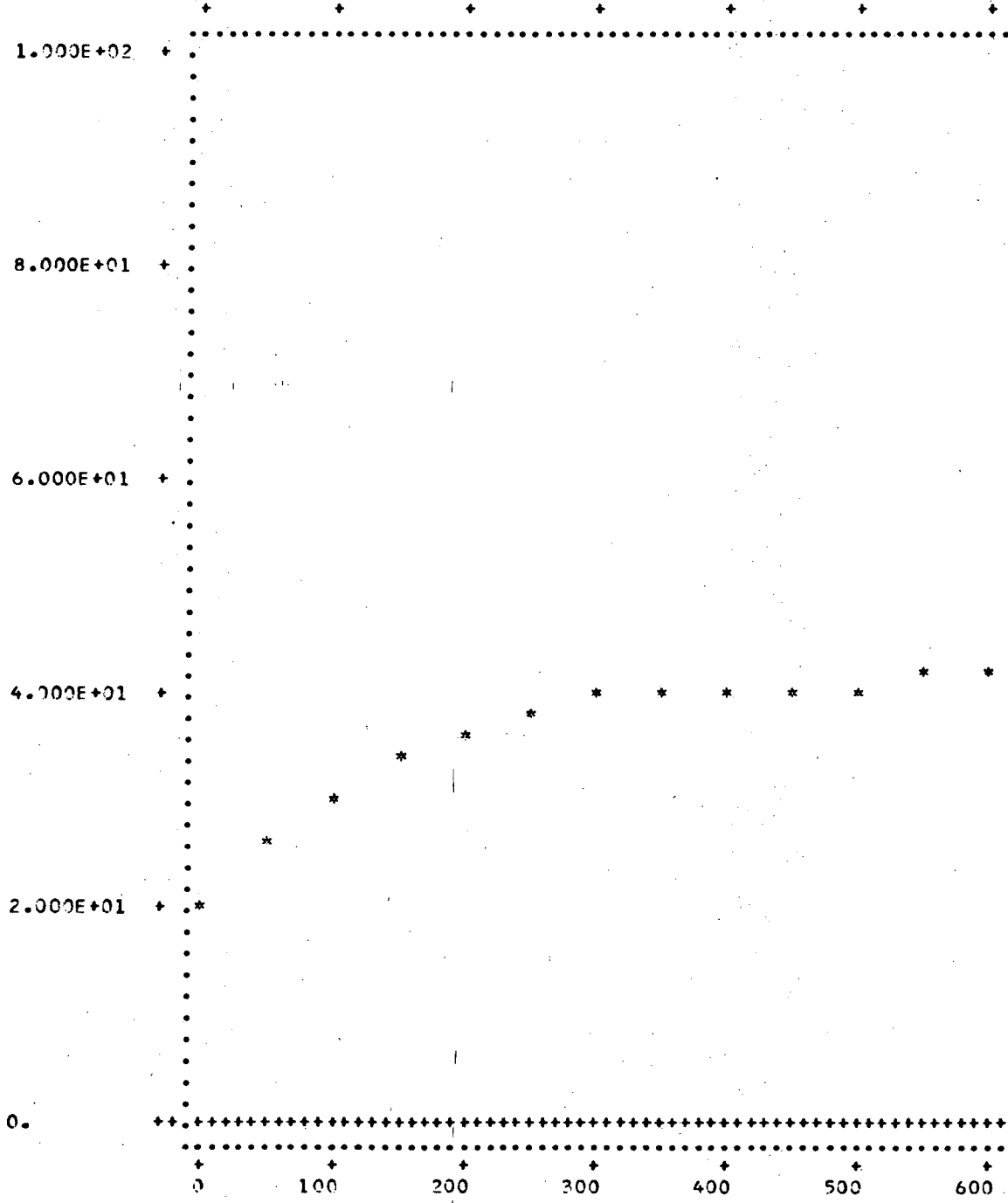
PHI = 75.00

N = 1.0000

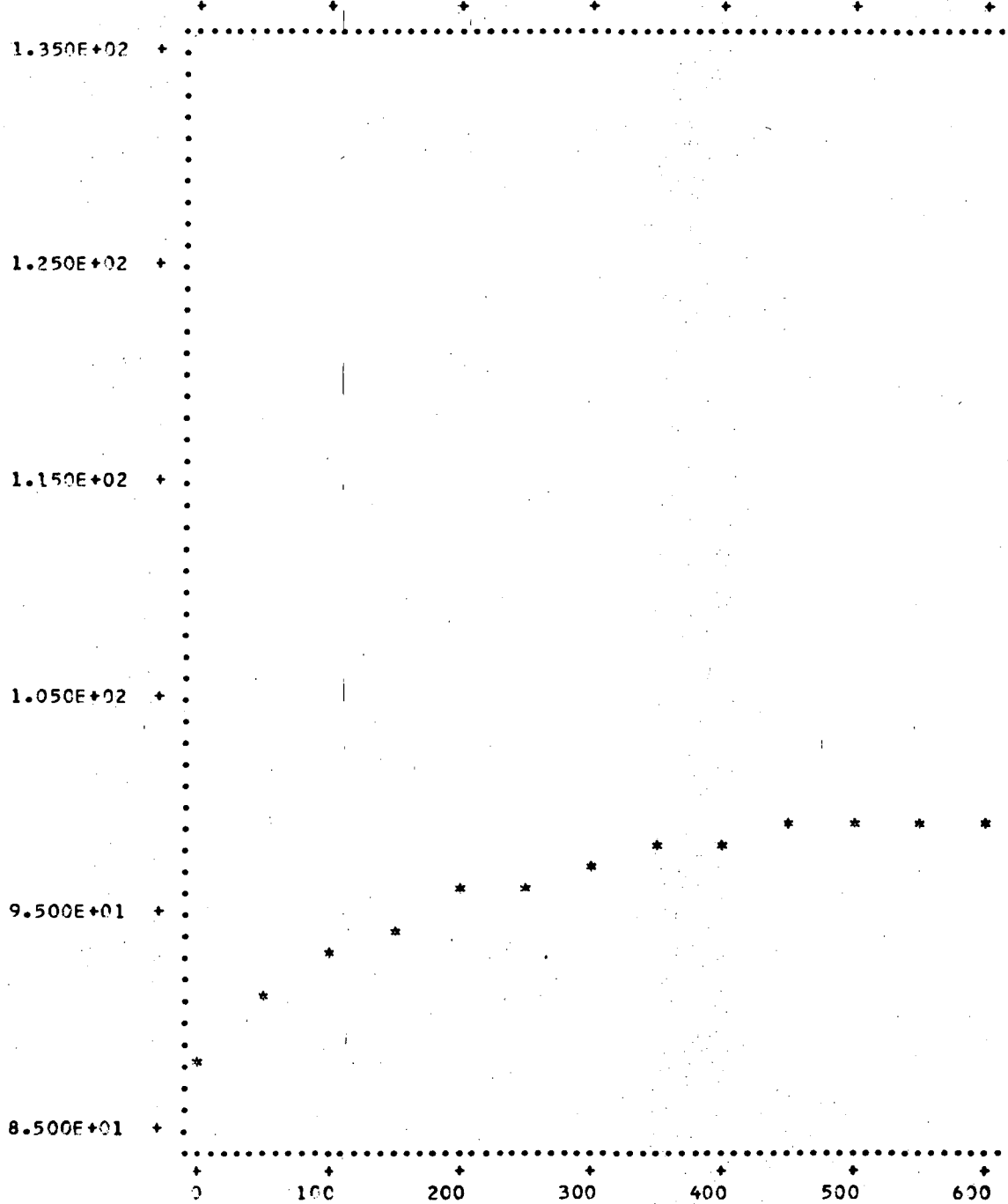
WAVELENGTH = 5461 A

NM - IK

NE - IKF = .3500 - I 2.3500



PC VERSUS FILM THICKNESS  
PHI = 75.00 N = 1.0000 WAVELENGTH = 5461 A NM - IK  
NF - IKF = .3500 - 1 2.3500



VII. FORTRAN IV Computer Program "PSIDEL"

This program has been written to convert ellipsometer azimuth-readings into relative phase  $\Delta$  and amplitude parameter  $\psi$ . According to Table I, it determines the zone of measurement and provides two or four-zone averages.

Variables Used in the Program

<u>Name</u>	<u>Symbol</u>	<u>Description</u>
AM	$A_m$	Azimuth reading of analyzer
PM	$P_m$	Azimuth reading of polarizer
Q	Q	Azimuth reading of compensator
DELM	$\Delta$	Relative phase change (deg)
PSIM	$\psi$	Arctangent of relative amplitude attenuation (deg)
N		Quantity of zones, over which one averages (4-zone measurement N = 4)

Input Format

<u>Card</u>	<u>Columns</u>		
	<u>1-10</u>	<u>11-20</u>	<u>21-30</u>
1	Title (up to 80 columns)		
2	N		
3	P <sub>1</sub>	A <sub>1</sub>	Q <sub>1</sub>
4	P <sub>2</sub>	A <sub>2</sub>	Q <sub>1</sub>
5	P <sub>3</sub>	A <sub>3</sub>	Q <sub>2</sub>
6	P <sub>4</sub>	A <sub>4</sub>	Q <sub>2</sub>

These 5 cards constitute 1 set for a 4-zone measurement. In case of a 2(1)-zone measurement, one set consists of only 4(3) cards. Two blank cards must follow the last set of data. The program, together with a sample output is reproduced below.

This program can be used as a subroutine in connection with program "CMOC", "OZOM" or "LAYER" in order to avoid the tedious use of the conversion table (Table I). Program "LAYER" was described by Gu,<sup>1</sup> but can also be found in the Appendix.

PSIDEL

```
PROGRAM PSIDEL (INPUT,OUTPUT)
C THIS PROGRAM USES AZIMUTH READINGS
C THIS PROGRAM COMPUTES PSI AND DEL FROM ELLIPSOMETER READINGS A
C P FROM ONE,TWO OR FOUR ZONES
C DIMENSION TITLE (8)
C EQUIVALENCE (PM,P),(AM,A)
7000 CONTINUE
READ 8,TITLE
8 FORMAT (8A10)
10 PRINT 9,TITLE
9 FORMAT (1H1,8A10)
16 P1=0.0
17 P2=0.0
17 P3=0.0
20 P4=0.0
20 A4=0.0
21 A3=0.0
21 A2=0.0
22 A1=0.0
23 READ 6,N
6 FORMAT (I1)
30 IF (N) 110,110,10
32 10 DO 99 J=1,N
34 1 READ 11,PM,AM,Q
11 FORMAT (3F10.0)
46 7 PRINT 207,PM,AM,Q
60 PM=PM + 90.
62 AM=AM + 90.
64 Q=Q + 90.
65 IF (P-180.0) 5,5,2
70 2 P=P-180.0
72 5 CONTINUE
72 IF (A-180.0) 4,4,3
75 3 A=A-180.0
77 4 CONTINUE
77 IF (Q-180.) 13,13,12
102 12 Q=Q-180.
104 13 CONTINUE
104 IF (Q-45.0) 105,20,39
107 20 IF (P-45.0) 21,21,22
112 21 IF (A-90.0) 63,63,83
115 22 IF (P-90.0) 23,23,24
120 23 IF (A-90.0) 74,74,54
123 24 IF (P-135.0) 25,25,26
126 25 IF (A-90.0) 81,81,61
131 26 IF (A-90.0) 52,52,72
134 39 IF (Q-135.0) 40,40,105
137 40 IF (P-45.0) 41,41,42
142 41 IF (A-90.0) 73,73,53
145 42 IF (P-90.0) 43,43,44
150 43 IF (A-90.0) 64,64,84
153 44 IF (P-135.0) 45,45,46
156 45 IF (A-90.0) 51,51,71
161 46 IF (A-90.0) 82,82,62
164 51 P1=270.0-2.0*P
167 A1=90.0-A
171 GO TO 99
```

```

172 52 P2=2.0*P-270.0
175   A2=90.0-A
177   GO TO 99
200 53 P3=90.0-2.0*P
203   A3=A-90.0
205   GO TO 99
205 54 P4=2.0*P-90.0
210   A4=A-90.0
212   GO TO 99
212 61 P1=2.0*P-90.0
215   A1=A-90.0
217   GO TO 99
217 62 P2=450.0-2.0*P
222   A2=A-90.0
224   GO TO 99
225 63 P3=2.0*P+90.0
230   A3=90.0-A
232   GO TO 99
232 64 P4=270.0-2.0*P
235   A4=90.0-A
237   GO TO 99
240 71 P1=450.0-2.0*P
243   A1=A-90.0
245   GO TO 99
246 72 P2=2.0*P-90.0
251   A2=A-90.0
253   GO TO 99
253 73 P3=270.0-2.0*P
256   A3=90.0-A
260   GO TO 99
261 74 P4=2.0*P+90.0
264   A4=90.0-A
266   GO TO 99
266 81 P1=2.0*P+90.0
271   A1=90.0-A
273   GO TO 99
273 82 P2=630.0-2.0*P
276   A2=90.0-A
300   GO TO 99
301 83 P3=2.0*P+270.0
304   A3=A-90.0
306   GO TO 99
307 84 P4=450.0-2.0*P
312   A4=A-90.0
314   GO TO 99
315 105 PRINT 208.0
208 FORMAT (1H0,4H0 = ,F5.2 //11HNO SOLUTION)
323 99 CONTINUE
326 100 DELM=(P1+P2 +P3+P4)/4.0
333   PSIM=(A1+A2+A3+A4)/4.0
337   IF (N.EQ.1) GO TO 102
342   IF (N.EQ.2) GO TO 103
343   IF (N.EQ.4) GO TO 104
345 102 DELM=DELM*4.0
347   PSIM=PSIM*4.0
350   GO TO 104
350 103 DELM=DELM*2.0
352   PSIM=PSIM*2.0

```



```
353 104 PRINT 204,P1,P2,P3,P4
367   PRINT 205,A1,A2,A3,A4
403   PRINT 206,DELM,PSIM
      204 FORMAT (1H0,5HP1 = ,F10.5,10X,5HP2 = ,F10.5,10X,5HP3 = ,F10.5,
      25HP4 = ,F10.5)
      205 FORMAT (1H0,5HA1 = ,F10.5,10X,5HA2 = ,F10.5,10X,5HA3 = ,F10.5,
      25HA4 = ,F10.5//)
      206 FORMAT (1H0,7HDELM = ,F10.5,10X,7HPSIM = ,F10.5)
      207 FORMAT (1H0,5HPM = ,F10.5,10X,5HAM = ,F10.5,10X,4HQ = ,F6.2)
413   GO TO 7000
414 110 CONTINUE
415   END
```

MGF2 ON CR (3.48)

\*\*\* PSIDEL \*\*\*\*

PM = 69.92700	AM = 140.71900	Q = 135.00	
PM = 159.71800	AM = 36.81200	Q = 135.00	
PM = 18.87500	AM = 142.47100	Q = 45.00	
PM = 108.70600	AM = 38.42400	Q = 45.00	
P1 = 52.25000	P2 = 49.85400	P3 = 52.58800	P4
A1 = 37.52900	A2 = 39.28100	A3 = 38.42400	A4

DELM = 51.03200

PSIM = 38.01150

VIII. FORTTRAN IV Computer Program "LAYER"

The program "LAYER" finds the thickness and complex refractive index of a single, absorbing film on an absorbing substrate.\* It does so by systematically combining all prescribed values of film thickness  $L$  and refractive index  $n_f - ik_f$  and calculating the  $\Delta$  and  $\psi$  for each combination. Whenever a particular combination of  $L$ ,  $n_f$  and  $k_f$  yields agreement with the experimentally determined quantities  $\Delta$  and  $\psi$  within a specified error  $\epsilon_\Delta$  and  $\epsilon_\psi$ , this combination appears in the output as a solution.

Input Format for Program "LAYER"

<u>Card</u>	<u>Col. 1</u>	<u>Col. 10</u>	<u>Col. 20</u>	<u>Col. 30</u>	<u>Col. 40</u>	<u>Col. 50</u>
1 } 2 }	Title and comments (up to 80 columns each)					
3	$n_o$	$\lambda_o$	$n_m$	$k_m$		
4	$n_{fi}$ (initial)	$\delta n_f$ (increment)	$n_{fm}$ (final)	$k_{fi}$ (initial)	$\delta k_f$ (increment)	$k_{fm}$ (final)
5	$L_i$ (initial)	$\delta L$ (increment)	$L_m$ (final)			
6	$\phi$	$\psi$	$\Delta$	$\epsilon_\psi$	$\epsilon_\Delta$	

These six cards constitute a set. Any number of sets may follow.

Three blank cards must follow the last set of data. Cards 1 and 2 of each set may contain any comments (or none at all) as desired. Their contents appear printed verbatim in the head of the output.

This program can be used to calculate theoretical values of  $\Delta$  and  $\psi$ , with changes in film thickness or with different film constants, by punching numbers greater than (or equal to) 90 for  $\epsilon_\Delta$  and a number

\*Based on an earlier FORTRAN II program "FILM".<sup>14</sup>

greater than (or equal to) 360 for  $\epsilon_{\Delta}$ . Entries for  $\psi$  and  $\Delta$  can be blank or any values such as 0.0.

The program, together with a sample of output, is reproduced on the following pages.

LAYER

```

PROGRAM LAYER (INPUT,OUTPUT)
C THIS PROGRAM IS INDEPENDENT OF ANGLE READINGS
C THIS PROGRAM CALCULATES THE THICKNESS AND COMPLEX REFRACTIVE
C INDEX OF A SINGLE ABSORBING FILM ON AN ABSORBING SUBSTRATE
COMPLEX TN2, TN3, CPHI2, CPHI3, R1S, R1P, R2S, R2P, D, RS, RP, RHO
DIMENSION TITLE (8), RANGE (8)
1 READ 2, TITLE,RANGE
2 FORMAT (8A10/8A10)
12 3 PRINT 4, TITLE,RANGE
4 FORMAT (1H1, 8A10//8A10)
22 5 READ 9, TN1,WL,TNS,TNKS
36 IF (TN1) 3000, 3000, 6
40 6 READ 10, TN1,DTN,TNM,TNKI,DTNK,TNKM
60 7 READ 11, TI,DT,TM
72 8 READ 12, PHI1,PSIM,DELM,EPSIM,EDELM
9 FORMAT (F9.0, 3F10.0)
10 FORMAT (F9.0, 5F10.0)
11 FORMAT (F9.0, 2F10.0)
12 FORMAT (F9.0, 4F10.0)
13 FORMAT (1H0,/6HPHI = ,F5.2,10X,4HN = ,F7.4, 10X, 13HWAVELENGTH = ,
C F5.0, 11H ANGSTROMS//32H REFRACTIVE INDEX OF SUBSTRATE = , F7.4,
C 2X, 4H- I, F7.4)
14 FORMAT (1H0, 27HREFRACTIVE INDEX OF FILM = , F7.4, 2X,
C 4H- I, F7.4//18H FILM THICKNESS = , F7.2, 10H ANGSTROMS,
C //8H PSIC = , F10.5, 10X, 7HDELC = , F10.5,
C //8H PSIM = , F10.5, 10X, 7HDELM = , F10.5)
15 FORMAT (1H0, 7HPSIM = , F10.5,10X, 7HDELM = , F10.5//32H NO SOLUT
C ION WITHIN GIVEN LIMITS)
110 M = 1
111 PHI = 0.01745329252*PHI1
113 CP = COS(PHI)
115 SP = SIN(PHI)
117 TN3 = CMPLX(TNS,-TNKS)
122 CPHI2 = CSQRT(1.0 - TN1**2*SP**2/(TN3**2))
145 TN = TN1
147 20 TNK = TNKI
151 30 T = TI
153 190 TN2 = CMPLX(TN,-TNK)
156 CPHI2 = CSQRT(1.0 - TN1**2*SP**2/(TN2**2))
201 R1S = (TN1*CP - TN2*CPHI2)/(TN1*CP + TN2*CPHI2)
233 R1P = -(TN1*CPHI2 - TN2*CP)/(TN1*CPHI2 + TN2*CP)
264 R2S = (TN2*CPHI2 - TN3*CPHI3)/(TN2*CPHI2 + TN3*CPHI3)
323 R2P = -(TN2*CPHI3 - TN3*CPHI2)/(TN2*CPHI3 + TN3*CPHI2)
361 D = (0.0,1.0)*(4.0*3.1415927*T/WL)*TN2*CPHI2
377 RS = (R1S + R2S*CEXP(-D))/(1.0 + R1S*R2S*CEXP(-D))
436 RP = (R1P + R2P*CEXP(-D))/(1.0 + R1P*R2P*CEXP(-D))
475 RHO = RP/RS
505 PSIC = ATAN(CABS(RHO))/0.01745329252
511 DELC = ATAN2(AIMAG(RHO), REAL(RHO))/0.01745329252
520 IF (DELC) 140,140,150
522 140 DELC = DELC + 360.00
524 150 IF (EPSIM - ABS(PSIC - PSIM)) 400, 200, 200
531 200 IF (EDELM - ABS(DELC - DELM)) 400, 200, 300
536 300 PRINT 13, PHI1,TN1,WL,TNS,TNKS
554 PRINT 14, TN,TNK,T,PSIC,DELC,PSIM,DELM
576 M = 2
577 400 IF(TM -T) 600,600,500

```

```
602      500 T = T + DT
604      GO TO 100
605      600 IF(TNKM - TNK) 800,800,700
610      700 TNK = TNK + DTNK
612      GO TO 30
613      800 IF(TNM - TN) 1000,1000,900
616      900 TN = TN + DTN
620      GO TO 20
621      1000 GO TO (2000, 1) M
627      2000 PRINT 13, PHI1, TN1, WL, TNS, TNKS
645      PRINT 15, PSIM, DELM
655      GO TO 1
656      3000 CONTINUE
657      END
```

Sample output, program LAYER

CU2O ON CU \*\*\* LAYER \*\*\*

TABLE 0 - 90 A

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = .9300 - I 2.3900  
REFRACTIVE INDEX OF FILM = 2.7500 - I .1950  
FILM THICKNESS = 0.00 ANGSTROMS  
PSIC = 36.00128            DELC = 72.80712  
PSIM = -0.00000            DELM = -0.00000

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = .9300 - I 2.3900  
REFRACTIVE INDEX OF FILM = 2.7500 - I .1950  
FILM THICKNESS = 30.00 ANGSTROMS  
PSIC = 36.39501            DELC = 65.76699  
PSIM = -0.00000            DELM = -0.00000

PHI = 75.00            N = 1.0000            WAVELENGTH = 5461    ANGSTROMS  
REFRACTIVE INDEX OF SUBSTRATE = .9300 - I 2.3900  
REFRACTIVE INDEX OF FILM = 2.7500 - I .1950  
FILM THICKNESS = 60.00 ANGSTROMS  
PSIC = 36.88396            DELC = 59.31852  
PSIM = -0.00000            DELM = -0.00000

IX. FORTTRAN IV Computer Program "FPLOTT"<sup>1</sup>

The program "FPLOTT" (Film Plot) calculates theoretical quantities of  $\psi$  and  $\Delta$  with changes in film thickness. Depending on the code number M, results are tabulated (as program LAYER) or given as curves or both.

Input data for program "FPLOTT" are arranged on cards as illustrated below:

<u>Card</u>	<u>Col. 1</u>	<u>Col. 10</u>	<u>Col. 20</u>	<u>Col. 30</u>	<u>Col. 40</u>	<u>Col. 50</u>
1 } 2 }	Title and comments (up to 80 columns)					
3	$n_o$	$\lambda_o$	$n_m$	$k_m$		
4	$n_{fi}$ (initial)	$\delta n_f$ (increment)	$n_{fm}$ (final)	$k_{fi}$ (initial)	$\delta k_f$ (increment)	$k_{fm}$
5	$L_i$	$\delta L$	$L_m$ (limited to 200 points)			
6	$\phi$	M				

These six cards constitute a set. Any number of sets may follow. In each set, the values of the optical constants of the film may be varied in increments if one desired. Three blank cards must follow the last set of cards.

M is the code number. The integer used for M determines how the results will be presented.



- M                      Format of Results
- 0      Results will be tabulated and given as three curves
- a)  $\psi$  vs  $\Delta$  curve with thickness as parameter
  - b)  $\psi$  vs film thickness
  - c)  $\Delta$  vs film thickness
- 1      Results will be tabulated only the  $\psi$  vs  $\Delta$  curve is plotted
- 2      Results will be tabulated and two curves will be plotted
- a)  $\psi$  vs film thickness
  - b)  $\Delta$  vs film thickness
- 3      Results will be given only as three curves
- a)  $\psi$  vs  $\Delta$
  - b)  $\psi$  vs film thickness
  - c)  $\Delta$  vs film thickness
- 4      Output has only the  $\psi$  vs  $\Delta$  curve
- 5      Two curves will be given
- a)  $\psi$  vs film thickness
  - b)  $\Delta$  vs film thickness

The maximum number of data points for L (thickness) is 200. If the  $\psi$  vs thickness and  $\Delta$  vs thickness curves are to be plotted, the maximum number is reduced to 101. The program "LAYER" should be used instead, if only tabulated results are wanted.

This program "FPLOT" has to utilize the subroutines "PRNPLT" and "PLSCAL" written by M. S. Itzkowitz to do the plotting of the curves. These two subroutines are library subroutines and they are stored in the computer (control data 7600 system).

A reproduction of the main program and the two subroutines is given on the following pages. A sample of the output curves is also given.

FPL0T

```

PROGRAM FPL0T (INPUT,OUTPUT)
C THIS PROGRAM IS INDEPENDENT OF ANGLE READINGS
C THIS PROGRAM CALCULATES DELC AND PSIC FROM FILM THICKNESS
C IT ALSO PLOTS PSIC VERSUS DELC CURVE WITH FILM THICKNESS AS PARAMETER
C AND PSIC VERSUS FILM THICKNESS, DELC VERSUS FILM THICKNESS.
C COMPLEX TN2, TN3, CPHI2, CPHI3, R1S, R1P, R2S, R2P, D, RS, RP, RHO
C DIMENSION TITLE (8), RANGE (8)
C DIMENSION XPLOT(200), YPLOT(200), ZPLOT(200)
1 READ 2, TITLE,RANGE
2 FORMAT (8A10/8A10)
12 3 PRINT 4, TITLE,RANGE
4 FORMAT (1H1, 8A10//8A10)
22 5 READ 9, TN1,WL,TNS,TNKS
36 IF (TN1) 3000, 3000, 6
40 6 READ 10, TN1,DTN,TNM,TNK1,DTNK,TNKM
60 7 READ 11, TI,DT,TM
72 IF (TI.NE.C.C) TD=TM-TI
75 8 READ 12, PHI1,M
9 FORMAT (F9.0, 3F10.0)
10 FORMAT (F9.0, 5F10.0)
11 FORMAT (F9.0, 2F10.0)
12 FORMAT (F9.0, 11 )
13 FORMAT (1H0,/6HPHI = ,F5.2,10X,4HN = ,F7.4, 10X, 13HWAVELENGTH = ,
C F5.0, 11H ANGSTROMS//33H REFRACTIVE INDEX OF SUBSTRATE = , F7.4,
C 2X, 4H- I, F7.4)
14 FORMAT (1H0, 27HREFRACTIVE INDEX OF FILM = , F7.4, 2X,
C 4H- I, F7.4//18H FILM THICKNESS = , F8.2, 10H ANGSTROMS,
C //8H PSIC = , F10.5, 10X, 7HDELC = , F10.5)
15 FORMAT (1H1)
16 FORMAT (22HPSIC VERSUS DELC CURVE)
17 FORMAT (6HPHI = ,F5.2,10X,4HN = ,F7.4,10X,13HWAVELENGTH = ,
C F5.0,4H A ,5X,13HNM - IKM = ,F7.4,2X,4H- I,F7.4)
18 FORMAT (13HNF - IKF = ,F7.4,2X,4H- I,F7.4)
19 FORMAT (26HDELC VERSUS FILM THICKNESS)
21 FORMAT (26HPSIC VERSUS FILM THICKNESS)
105 PHI = 0.01745329252*PHI1
107 CP = COS(PHI)
111 SP = SIN(PHI)
113 TN3 = CMPLX(TNS,-TNKS)
117 CPHI3 = CSQRT(1.0 - TN1**2*SP**2/(TN3**2))
141 TN = TN1
143 2C TAK = TNK1
145 3C T = TI
146 NPOINT = J
150 1)0 TN2 = CMPLX(TN,-TNK)
153 CPHI2 = CSQRT(1.0 - TN1**2*SP**2/(TN2**2))
176 R1S = (TN1*CP - TN2*CPHI2)/(TN1*CP + TN2*CPHI2)
230 R1P = -(TN1*CPHI2 - TN2*CP)/(TN1*CPHI2 + TN2*CP)
261 R2S = (TN2*CPHI2 - TN3*CPHI3)/(TN2*CPHI2 + TN3*CPHI3)
320 R2P = -(TN2*CPHI3 - TN3*CPHI2)/(TN2*CPHI3 + TN3*CPHI2)
356 D = (0.0,1.0)*(4.0*3.1415927*T/WL)*TN2*CPHI2
374 RS = (R1S + R2S*CEXP(-D))/(1.0 + R1S*R2S*CEXP(-D))
433 RP = (R1P + R2P*CEXP(-D))/(1.0 + R1P*R2P*CEXP(-D))
472 RHO = RP/RS
502 PSIC = ATAN(CABS(RHO))/0.01745329252
506 DELC = ATAN2(AIMAG(RHO), REAL(RHO))/0.01745329252
515 IF (DELC) 140,140,150

```

```
517 140 DELC = DELC + 360.00
521 150 IF(M.GT.2) GO TO 300
525 PRINT 13, PH11,TN1,WL,TNS,TNKS
542 PRINT 14, TN,TNK,T,PSIC,DELC
561 300 XPLOT(NPOINT) = DELC
562 YPLOT(NPOINT) = PSIC
564 IF(M.EQ.1.OR.M.EQ.4) GO TO 400
574 IF(TI.EQ.0.0) GO TO 3500
575 ZPLOT(NPOINT) = T - TD
600 GO TO 400
600 3500 ZPLOT(NPOINT) = T
602 400 NPOINT = NPOINT + 1
604 IF(TM - T) 600,600,500
607 500 T = T + DT
611 GO TO 100
612 600 NPOINT = NPOINT - 1
614 IF(M.EQ.2.OR.M.EQ.5) GO TO 1500
623 PRINT 15
626 PRINT 16
632 PRINT 17, PH11,TN1,WL,TNS,TNKS
650 PRINT 18, TN,TNK
660 CALL PRNPLT(XPLOT,YPLOT,360.,5.0,90.,2.0,0.,0.,NPOINT)
671 IF(M.EQ.1.OR.M.EQ.4) GO TO 1100
701 1500 PRINT 15
705 PRINT 21
711 PRINT 17, PH11,TN1,WL,TNS,TNKS
727 PRINT 18, TN,TNK
737 IF(TI.EQ.0.0) GO TO 3100
740 PRINT 3300, TD
746 3300 FORMAT (5HADD ,F8.2,17HTO SCALE READINGS)
757 CALL PRNPLT(ZPLOT,YPLOT,TD,100.,90.,2.,0.,0.,NPOINT)
760 GO TO 3400
760 3100 CALL PRNPLT(ZPLOT,YPLOT,TD,100.,90.,2.,0.,0.,NPOINT)
771 3400 PRINT 15
775 PRINT 19
1001 PRINT 17, PH11,TN1,WL,TNS,TNKS
1017 PRINT 18, TN,TNK
1027 IF(TI.EQ.0.0) GO TO 3200
1030 PRINT 3300, TD
1036 CALL PRNPLT(ZPLOT,XPLOT,TD,100.,360.,10.,0.,0.,NPOINT)
1047 GO TO 1100
1050 3200 CALL PRNPLT(ZPLOT,XPLOT,TD,100.,360.,10.,0.,0.,NPOINT)
1061 1100 IF(TNKM - TNK) 800,800,700
1064 700 TNK = TNK + DTNK
1066 GO TO 30
1067 800 IF(TNM - TN) 1000,1000,900
1072 900 TN = TN + DTN
1074 GO TO 20
1075 1000 GO TO 1
1076 3000 CONTINUE
1077 END
```

PROGRAM LENGTH INCLUDING I/O BUFFERS

03667

PRNPLT

```
      SUBROUTINE PRNPLT(X,Y,XMAX,XINCR,YMAX,YINCR,ISX,ISY,NPTS)
C     PRINTER PLOT ROUTINE      M.S.ITZKOWITZ    MAY,1967
C
C     PLOTS THE *NPTS* POINTS GIVEN BY *X(I),Y(I)* ON A 51 X 101 GRID
C     USING A TOTAL OF 56 LINES ON THE PRINTER
C     IF *ISX* OR *ISY* ARE NON-ZERO, THE CORRESPONDING MAXIMUM AND
C     INCREMENTAL STEP SIZE ARE COMPUTED
C     IF EITHER INCREMENTAL STEP SIZE IS ZERO, THE PROGRAM EXITS
C     NEITHER OF THE INPUT ARRAYS ARE DESTROYED. IF SCALING IS DONE
C     THE CORRESPONDING NEW VALUES OF MAXIMUM AND STEP SIZE ARE RETURNED
C
      DIMENSION X(NPTS),Y(NPTS),IGRID(105),XAXIS(11)
C
      INTEGER BLANK,DOT,STAR,IGRID,PLUS
      DATA BLANK,DOT,STAR,PLUS / 1H ,1H.,1H*,1H+ /
C
901  FORMAT(14X,105A1)
902  FORMAT(1X,F10.3,2X,1H+,105A1,1H+)
903  FORMAT(15X,103(1H.))
904  FORMAT(7X,11(F10.0),2H (,14,5H PTS) )
905  FORMAT(16X,11(1H+,9X))
9800 FORMAT(46H1SCALING ERROR IN PRNPLT, EXECUTION TERMINATED )
C
      IF(ISX.NE.0) CALL PLSCAL(X,XMAX,XINCR,NPTS,100)
      IF(ISY.NE.0) CALL PLSCAL(Y,YMAX,YINCR,NPTS,50)
      IF(XINCR.EQ.0..OR.YINCR.EQ.0.) GO TO 800
      YAXMIN=0.01*YINCR
      XAXMIN=0.01*XINCR
      IZERO=YMAX/YINCR+1.5
      JZERO=103.5-XMAX/XINCR
      IF(JZERO.GT.103..OR.JZERO.LT.4) JZERO=2
      PRINT 905
      PRINT 903
      DO 10 I=1,51
103  IF ( I.NE.IZERO) GO TO 16
104  DO 14 J=1,105
112  14  IGRID(J)=PLUS
113  GO TO 15
117  16  DO 11 J=1,105
125  11  IGRID(J)=BLANK
132  15  IGRID(JZERO)=PLUS
133  IGRID(104)=DOT
136  IGRID(2)=DOT
137  DO 12 K=1,NPTS
140  ITEST =(YMAX-Y(K))/YINCR+1.5
144  IF(ITEST .NE.1) GO TO 12
146  J=103.5-(XMAX-X(K))/XINCR
152  IF(J.GT.103)J=105
156  IF(J.LT.3) J=1
162  IGRID(J)=STAR
164  12  CONTINUE
167  IF(MOD(I,10).EQ.1) GO TO 13
174  PRINT 901,IGRID
201  GO TO 10
205  13  YAXIS=YMAX-(I-1)*YINCR
211  IF(ABS(YAXIS).LT.YAXMIN) YAXIS=0.
216  PRINT 902,YAXIS,(IGRID(J),J=1,105)
```

```
232 10 CONTINUE
234 PRINT 903
240 PRINT 905
247 DO 20 M=1,11
254 XAXIS(M)=XMAX-XINCR*(FLOAT(11-M))*10.0
257 IF (ABS(XAXIS(M)).LT.XAXMIN) XAXIS(M)=0.
266 20 CONTINUE
270 PRINT 904,XAXIS,NPTS
300 RETURN
301 800 PRINT 9800
305 CALL EXIT
306 END
```

PLSCAL

```
      SUBROUTINE PLSCAL(V,VMAX,VINCR,NPTS,NDIVIS)
C
C   SCALING PROGRAM FOR USE WITH PPNPLT   M.S.ITZKOWITZ   MAY,1967
C   THIS VERSION ADJUSTS THE FULL SCALE TO 2.5,5.0, OR 10. TIMES 10**N
C   AND ADJUSTS THE MAXIMUM POINT TO AN INTEGER MULTIPLE OF 5*VINCR
C
C   DIMENSION V(NPTS)
C
      VMIN=V(1)
      VMAX=V(1)
10     DO 10 I=1,NPTS
11       IF(V(I).LT.VMIN) VMIN=V(I)
12       IF(V(I).GT.VMAX) VMAX=V(I)
16     ORANGE=VMAX-VMIN
23     CONTINUE
25   10  IF(ORANGE.EQ.0.) GO TO 8000
27     ORANGE=0.4342944*ALOG(ORANGE)
30     IF(ORANGE)20,20,30
32     IRANGE=ORANGE
37   30  GO TO 40
41     IRANGE=-ORANGE
42   20  IRANGE=-IRANGE-1
43     ORANGE=ORANGE-FLOAT(IRANGE)
46   40  ORANGE=ORANGE-FLOAT(IRANGE)
50     RANGE=10.**ORANGE
C
C   RANGE IS BETWEEN 1.0 AND 10.0
C
53   43  IF(RANGE.GT.2.5) GO TO 41
57     RANGE=2.5
57     GO TO 50
60   41  IF(RANGE.GT.5.0) GO TO 42
64     RANGE=5.0
64     GO TO 50
65   42  RANGE=10.0
67   50  TRANGE=RANGE*(10.**IRANGE)
C
C   TRANGE IS NOW 2.5,5.0, OR 10.0 TIMES A POWER OF TEN
C
73     VINCR=TRANGE/FLOAT(NDIVIS)
75     IF(VMAX)51,51,52
77   52  IMAX=VMAX/(5.0*VINCR)
101     XMAX=5.0*VINCR*FLOAT(IMAX+1)
104     GO TO 53
105   51  IMAX=-VMAX/(5.0*VINCR)
110     XMAX=5.0*VINCR*FLOAT(-IMAX+1)
113   53  IF(VMIN.GT.XMAX-TRANGE) GO TO 100
120     RANGE=RANGE*2.0
121     IF(RANGE-10.) 43,43,54
124   54  RANGE=RANGE/10.
126     IRANGE=IRANGE+1
127     GO TO 43
130   100 VMAX=XMAX
131     VMIN=XMAX-TRANGE
133     RETURN
134   8000 PRINT 9800
      9800 FORMAT(45H1PLSCAL CALLED TO SCALE ARRAY WITH ZERO RANGE)
143     CALL EXIT
144     END
```

PSIC VERSUS FILM THICKNESS

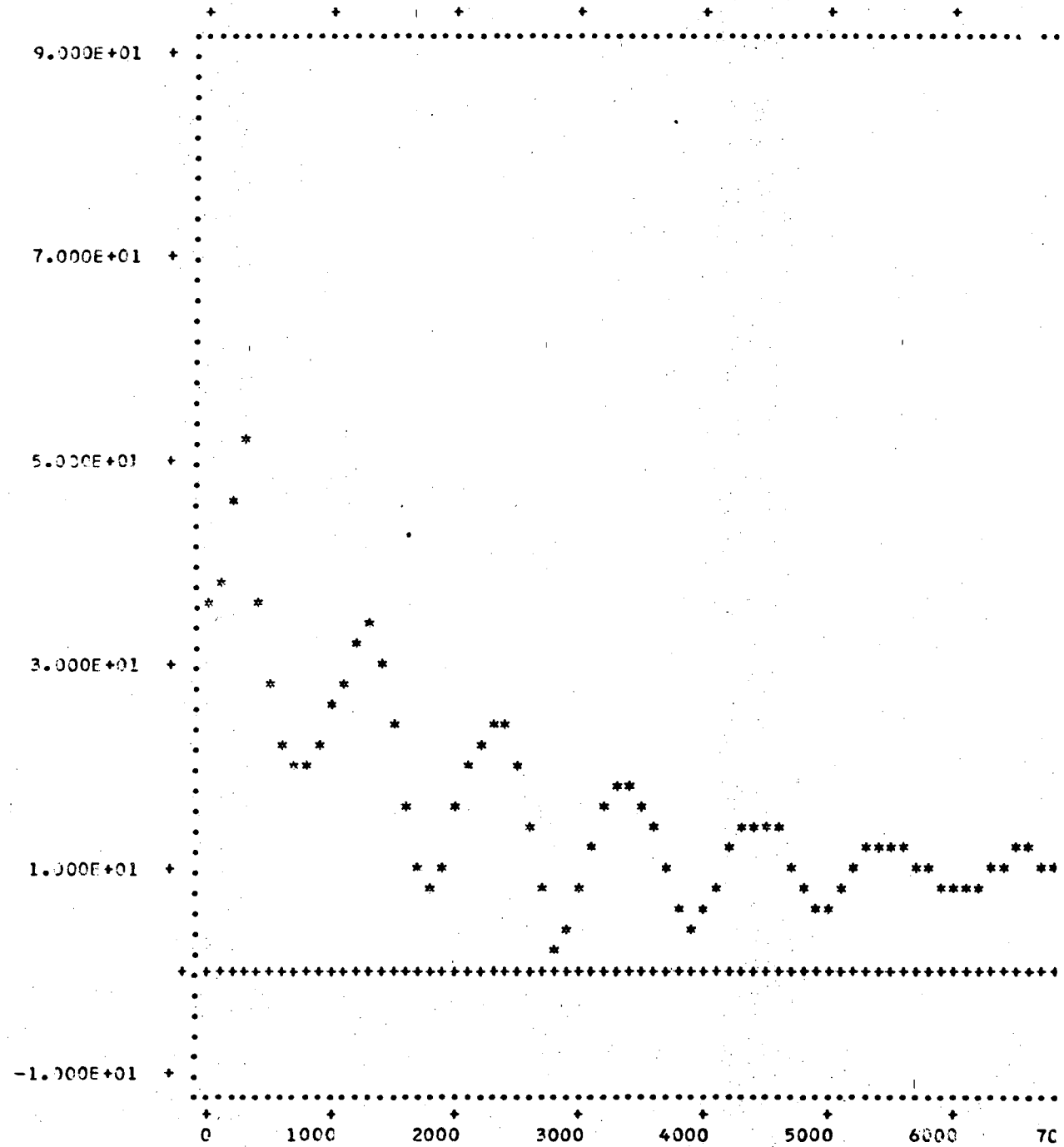
PHI = 75.00

N = 1.0000

WAVELENGTH = 5461 A

NM - IKM = .

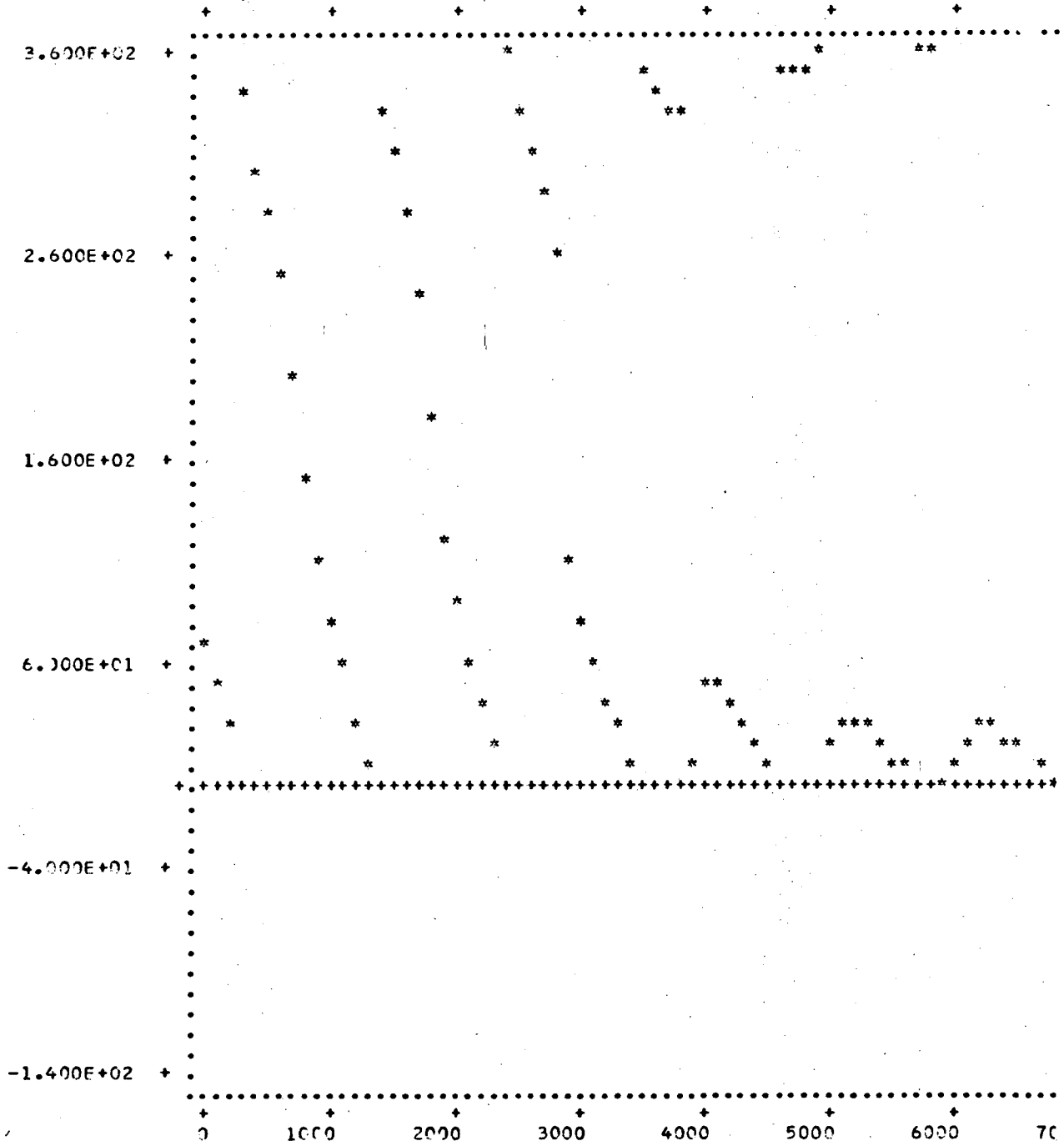
MF - IKF = 2.7500 - I .1950





DELTA VERSUS FILM THICKNESS  
PHI = 75.00 N = 1.0000  
NF - IKF = 2.7500 - I .1950

WAVELENGTH = 5461 A NM - IKM = .



ACKNOWLEDGEMENT

The author is grateful to R. H. Muller for his advice and stimulating discussions. I wish to thank the Deutsche Forschungsgemeinschaft for its financial support.

This work was done under the auspices of the U. S. Atomic Energy Commission.

REFERENCES

1. H. Gu, Ellipsometry of Surface Layers (M. S. Thesis) LBL-165 (1971).
2. W. Koenig, in Handbuch der Physik, H. Geiger and K. Scheel, eds. (Springer, Berlin, 1928) Vol. XX, p. 141, p. 240.
3. E. E. Bell, in Encyclopedia of Physics, S. Fluegge and L. Genzel, eds., (Springer-Verlag, 1967) Vol. XXV/2a, p. 1.
4. R. H. Muller, in Advances in Electrochemistry and Electrochemical Engineering (Wiley Interscience, to be published) Vol. 9, p. 167-226.
5. R. W. Ditchburn, Light (Interscience Publ., 1964) Vol. II, p. 590.
6. R. H. W. Graves, J. Opt. Soc. Am. 59, 1225 (1969).
7. M. Born and E. Wolf, Principles of Optics (MacMillian Co., New York, 1964) 2nd Ed., Ch. I, XIII.
8. F. L. McCrackin, A. Fortran Program for Analysis of Ellipsometer Measurements, U. S. Dept. of Commerce, NBS, Technical Note No. 479, 1969.
9. D. A. Holmes and D. L. Feucht, J. Opt. Soc. Am. 57, 466 (1967).
10. P. Drude, Ann. Physik u. Chemie, N. F., 36, 865 (1889).
11. A. Vasićek, J. Opt. Soc. Am. 37, 145 (1947).
12. R. H. Muller, Surf. Sci. 16, 14 (1969).
13. J. R. Mowat and R. H. Muller, Reflection of Polarizer Light from Absorbing Media, UCRL-11813 (Aug. 1966).
14. J. R. Mowat and R. H. Muller, Reflection of Polarized Light from Film-Covered Surfaces, UCRL-17128 (Feb. 1967).

Table I. Derivation of  $\psi$  and  $\Delta$  from ellipsometer azimuths.

Zone	Range of Polarizer Transmission Azimuth p	Compensator Fast Axis Azimuth q	Range of Analyzer Transmission Azimuth a	$\psi$	$\Delta$
A-1	0-45	45	90-180	180-a	90-2p
A-2	45-90	135	90-180	180-a	2p-90
A-3	90-135	45	0-90	a	270-2p
A-4	135-180	135	0-90	a	2p-270
B-1	0-45	135	0-90	a	90+2p
B-2	45-90	45	0-90	a	270-2p
B-3	90-135	135	90-180	180-a	2p-90
B-4	135-180	45	90-180	180-a	450-2p
C-1	0-45	45	0-90	a	270-2p
C-2	45-90	135	0-90	a	90+2p
C-3	90-135	45	90-180	180-a	450-2p
C-4	135-180	135	90-180	180-a	2p-90
D-1	0-45	135	90-180	180-a	270-2p
D-2	45-90	45	90-180	180-a	450-2p
D-3	90-135	135	0-90	a	90+2p
D-4	135-180	45	0-90	a	630-2p

00003901322

Table II. Fortran functions used in the programs.

Name	Evaluates	Converts
CSQRT (C)	$\sqrt{C}$	complex to complex
CEXP (C)	$e^C$	complex to complex
CABS (C)	$ C $	complex to real
AIMAG (C)	finds the imaginary part of C	complex to real
REAL (C)	finds the real part of C	complex to real
COX (X)	$\cos X$	real to real
SIN (X)	$\sin X$	real to real
ATAN (X)	$\tan^{-1} X$	real to real
ATAN2 (X,Y)	$\tan^{-1}(x/y)$	real to real
ABS (X)	$ X $	real to real
CMPLX (A,B)	constructs $A+iB$ from A,B	real to complex

If C is complex, A, B, X, Y are real.

LEGAL NOTICE

*This report was prepared as an account of work sponsored by the United States Government. Neither the United States nor the United States Atomic Energy Commission, nor any of their employees, nor any of their contractors, subcontractors, or their employees, makes any warranty, express or implied, or assumes any legal liability or responsibility for the accuracy, completeness or usefulness of any information, apparatus, product or process disclosed, or represents that its use would not infringe privately owned rights.*

TECHNICAL INFORMATION DIVISION  
LAWRENCE BERKELEY LABORATORY  
UNIVERSITY OF CALIFORNIA  
BERKELEY, CALIFORNIA 94720